

Supporting information

Efficient SF₆ capture and separation in robust gallium- and vanadium metal-organic frameworks

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Section S1. Materials and methods

Materials

N,N-dimethylformamide (DMF), and Acetic acid $\geq 99\%$ were purchased from VWR International AB, Sweden. Vanadyl(IV) sulfate hydrate ($\text{VOSO}_4 \cdot x\text{H}_2\text{O}$), Gallium(III) nitrate hydrate ($\text{Ga}(\text{NO}_3)_3 \cdot x\text{H}_2\text{O}$), 1,3,6,8-tetrakis(4-carboxyphenyl)pyrene (H_4TBAPy), and 1,2,4,5-tetrakis(4-carboxyphenyl)benzene (H_4TCPB) were purchased from Sigma-Aldrich, USA. All chemicals were used as received without further purification.

Preparation of V-TBAPy and -TCPB

In a typical procedure, $\text{VOSO}_4 \cdot x\text{H}_2\text{O}$ (0.20 mmol) and H_4TBAPy (0.20 mmol) were dispersed in 10 ml DMF. The yellow dispersion was thereafter transferred to a 25 ml Teflon—lined stainless steel autoclave and heated at 180 °C for 72 h. The obtained green product was collected by centrifugation at 3,800 rpm for 20 min, washed once with deionized water and twice with DMF, and finally dried overnight in a ventilated oven at 70 °C. V-TCPB was synthesized in the same manner using H_4TCPB (0.20 mmol) as the organic linker instead.

Preparation of Ga-TBAPy and -TCPB

Ga-TBAPy was prepared from a solvothermal synthesis of $\text{Ga}(\text{NO}_3)_3 \cdot x\text{H}_2\text{O}$ (0.167 mmol) and H_4TBAPy (0.167 mmol) in a mixture of 11.5 mL DMF and 1.0 mL acetic acid at 120 °C for 48 h in a Teflon-lined stainless steel autoclave. The product was collected by centrifugation at 3,800 rpm for 20 min, washed with DMF three times, and finally dried overnight in a ventilated oven at 70 °C. Similarly, Ga-TCPB was synthesized according to the same procedure using H_4TCPB as the linker.

Characterization

Powder X-ray diffraction (PXRD) diffractograms were recorded on a Bruker D8 Advanced Powder diffractometer (Bruker, Bremen, Germany) operated at 40 kV and 40 mA, using Cu K α radiation ($\lambda = 1.5418 \text{ \AA}$), a step-size of 0.02 ° and a time-per-step of 0.5 s. Scanning electron microscopy (SEM) images were obtained on a Zeiss Merlin Field Emission Scanning Electron Microscope (Oberkochen, Germany) using an acceleration voltage of 2.5 kV and a probe current of 80 pA. All samples were sputter-coated with a thin layer of Pd/Au prior to imaging.

Section S2. Structure determination

The structures of the Ga- and V-based MOFs were determined using 3-dimensional electron diffraction (3D ED) combined with high-resolution transmission electron microscopy (HRTEM) imaging, as well as structure modeling. The samples were dispersed in absolute ethanol and a droplet of the suspensions was transferred onto carbon-coated copper grids. The 3D ED data sets were collected on a JEOL JEM-F200 TEM (Tokyo, Japan) operated at an accelerating voltage of 200 kV using an ASI Cheetah 1800 detector under continuous tilting mode. The data was analyzed and visualized using the software *EDT PROCESS*¹ for the determination of unit-cell parameters and reflection conditions and processed by the X-ray Detector Software *XDS*² for extraction of reflection intensities which were subsequently used for structure solution. Using *Olex2*³, the structure was solved with the integrated space-group and crystal-structure determination program *SHELXT*⁴ using Intrinsic Phasing and refined with the *SHELXL*⁵ refinement package using Least Squares minimization. Selected area electron diffraction (SAED) and HRTEM images were obtained on a JEOL JEM-2100Plus TEM (Tokyo, Japan) using a TVIPS XF416 detector.

Le Bail and Rietveld refinements^{6, 7} of the MOFs were performed using the crystallographic program *JANA*⁸ over the full sampled angular range based on space group *P2/m* for V- and Ga-TBAPy, Ga-TCPB, and *Pcma* for V-TCPB. The Bragg peaks were modeled by a Pseudo-Voigt peak-shape function modified for asymmetry, with six coefficients that could be refined. The background was treated using a Legendre polynomial with six parameters that could be refined for the samples. The starting atomic coordinates were adopted from the model obtained by 3D ED data. Because of the complexity of the structural model, constraints on V-O, Ga-O, C-O, and C-C distances were applied, and their weight was removed in the final cycles. All materials were visualized by using the 3D visualization program *VESTA*⁹.

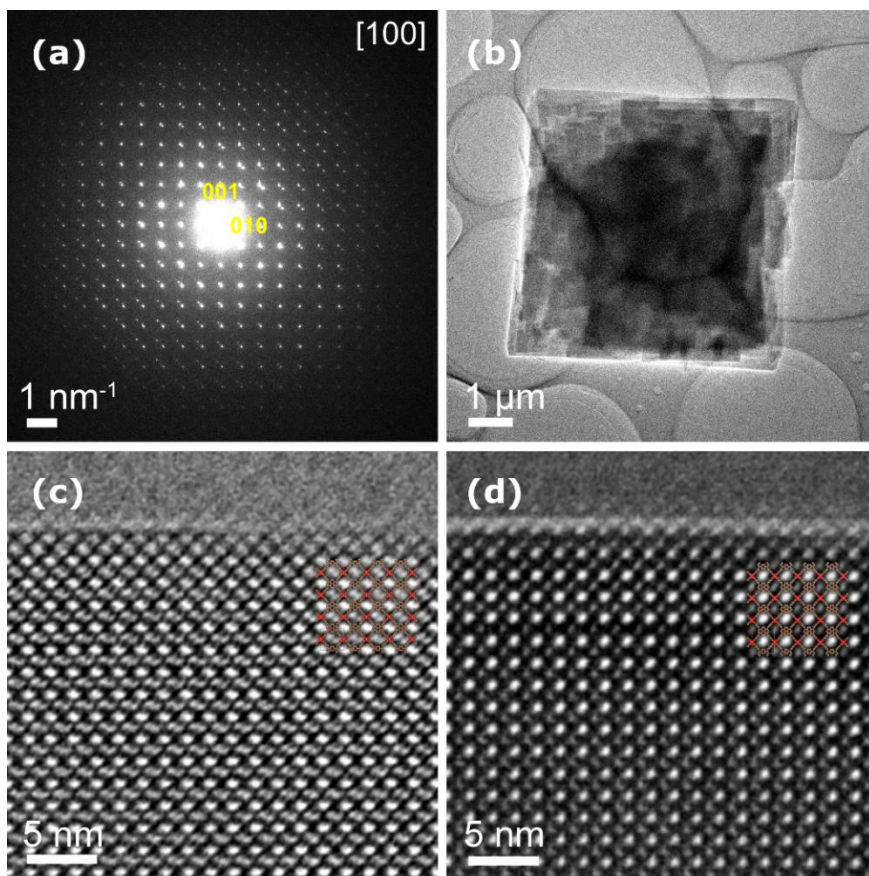


Fig. S1. (a) Selected area electron diffraction pattern, (b) low magnification bright-field image, and (c – d) corresponding high-resolution TEM images of V-TBAPy with an insert of the structure model.

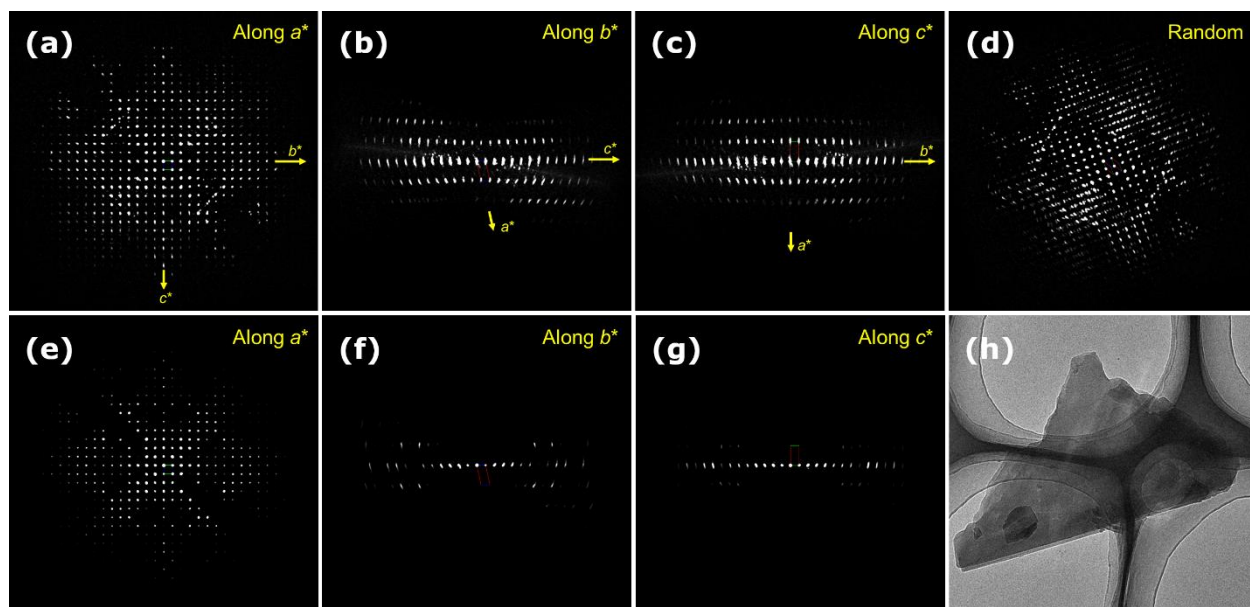


Fig. S2. (a – d) projection view of the 3D reciprocal lattice of V-TBAPy, (e – g) 2D slices from the reconstructed 3D reciprocal lattice as obtained from the 3D ED data, and (h) low magnification bright-field image of the crystal.

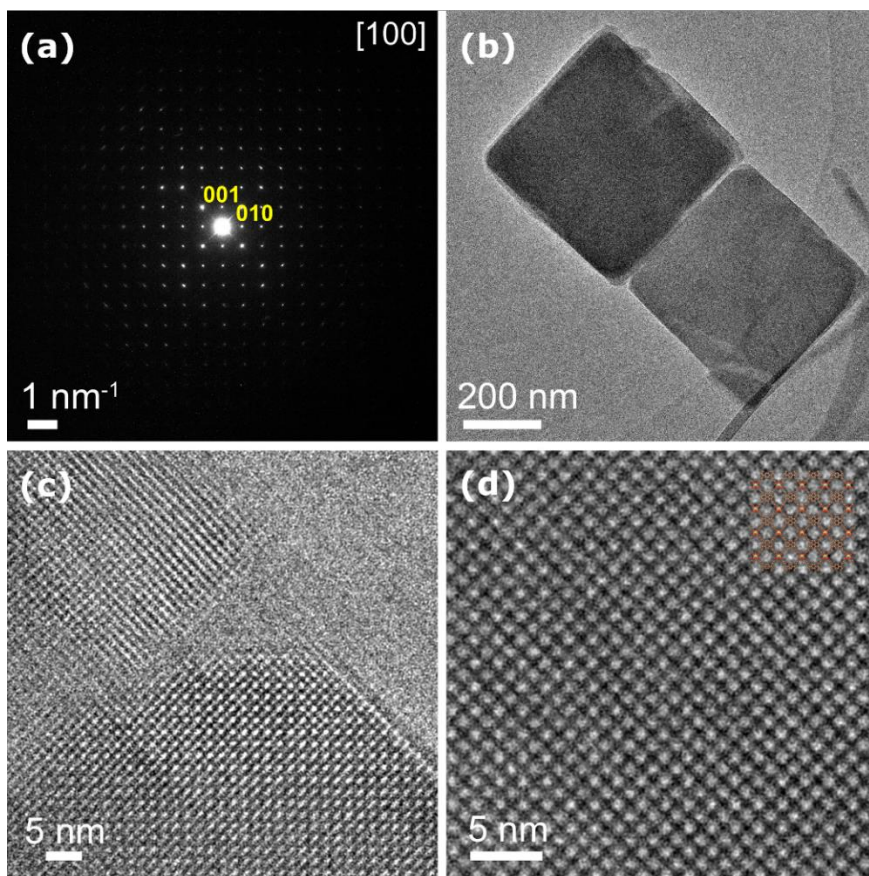


Fig. S3. (a) Selected area electron diffraction pattern, (b) low magnification bright-field image, and (c – d) corresponding high-resolution TEM images of Ga-TBAPy with an insert of the structure model.

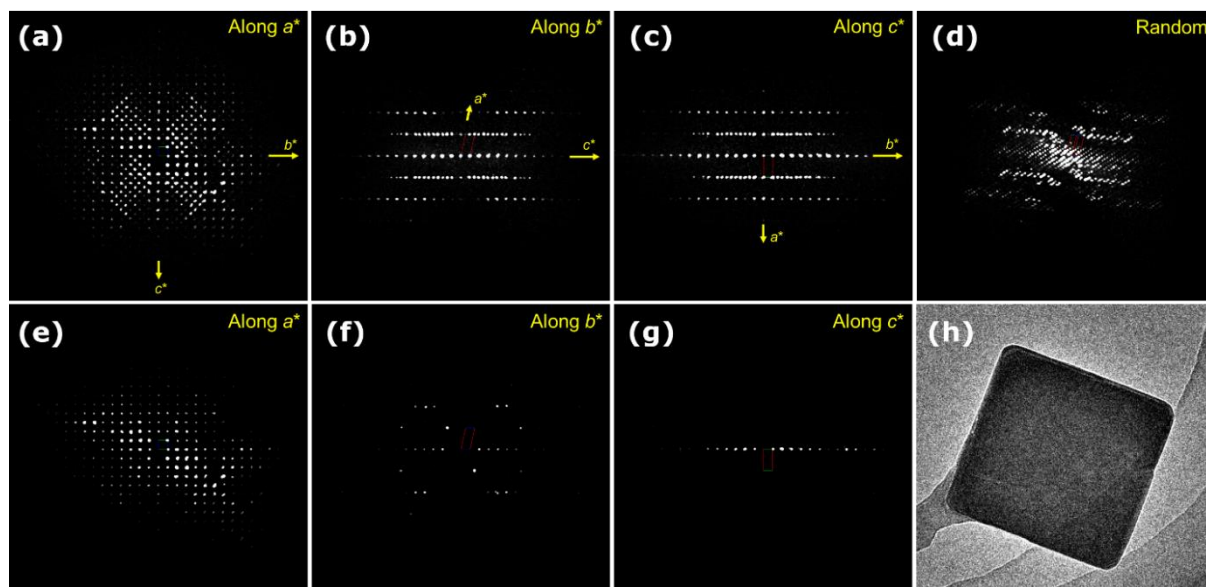


Fig. S4. (a – d) projection view of the 3D reciprocal lattice of Ga-TBAPy, (e – g) 2D slices from the reconstructed 3D reciprocal lattice as obtained from the 3D ED data, and (h) low magnification bright-field image of the crystal.

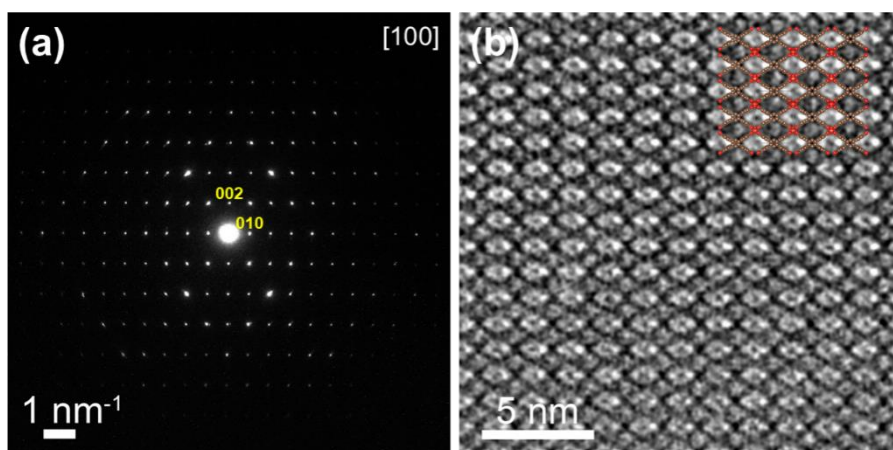


Fig. S5. (a) Selected area electron diffraction pattern and (b) the corresponding high-resolution TEM image of V-TCPB with an insert of the structure model.

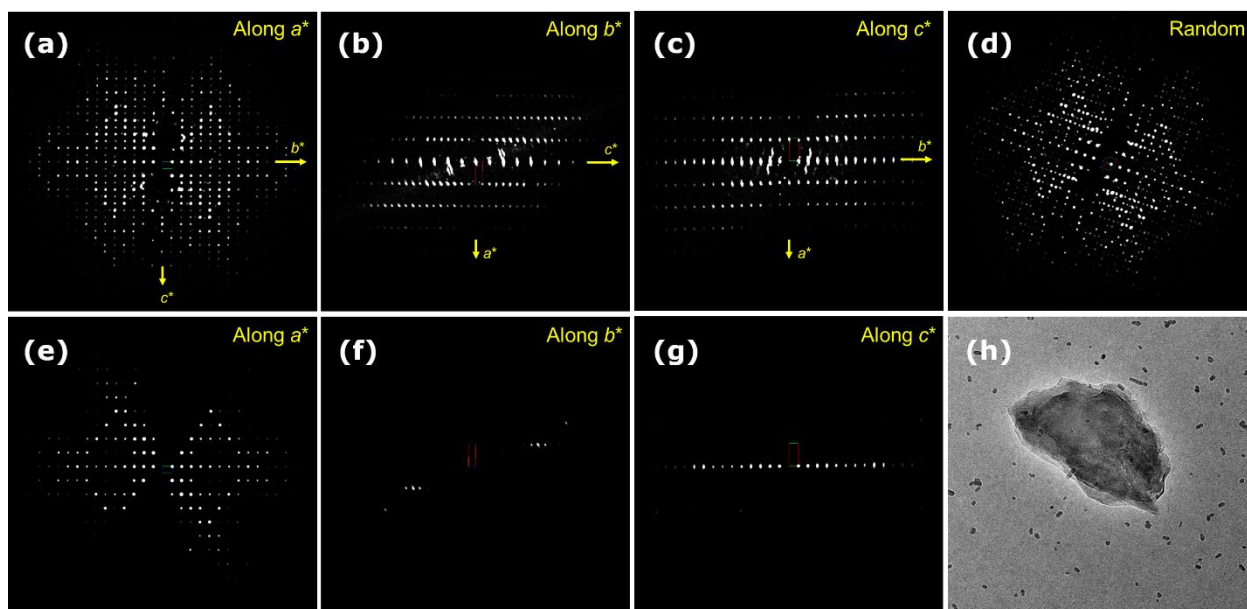


Fig. S6. (a – d) projection view of the 3D reciprocal lattice of V-TCPB, (e – g) 2D slices from the reconstructed 3D reciprocal lattice as obtained from the 3D ED data, and (h) low magnification bright-field image of the crystal.

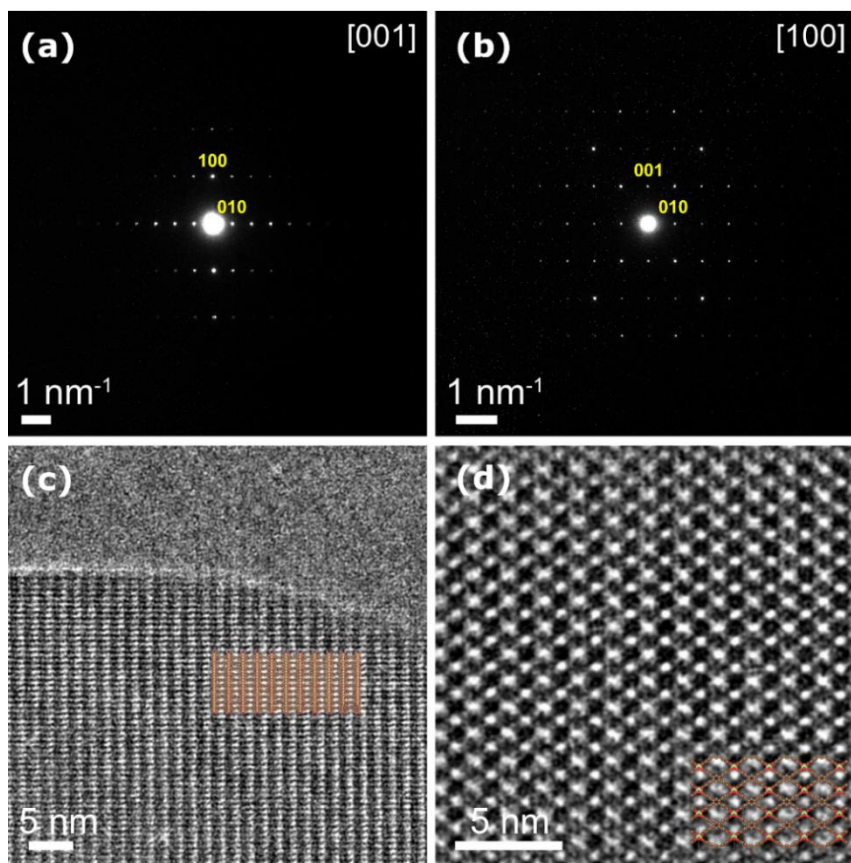


Fig. S7. (a – b) Selected area electron diffraction patterns and (c – d) the corresponding high-resolution TEM images of Ga-TCPB with inserts of the structure model.

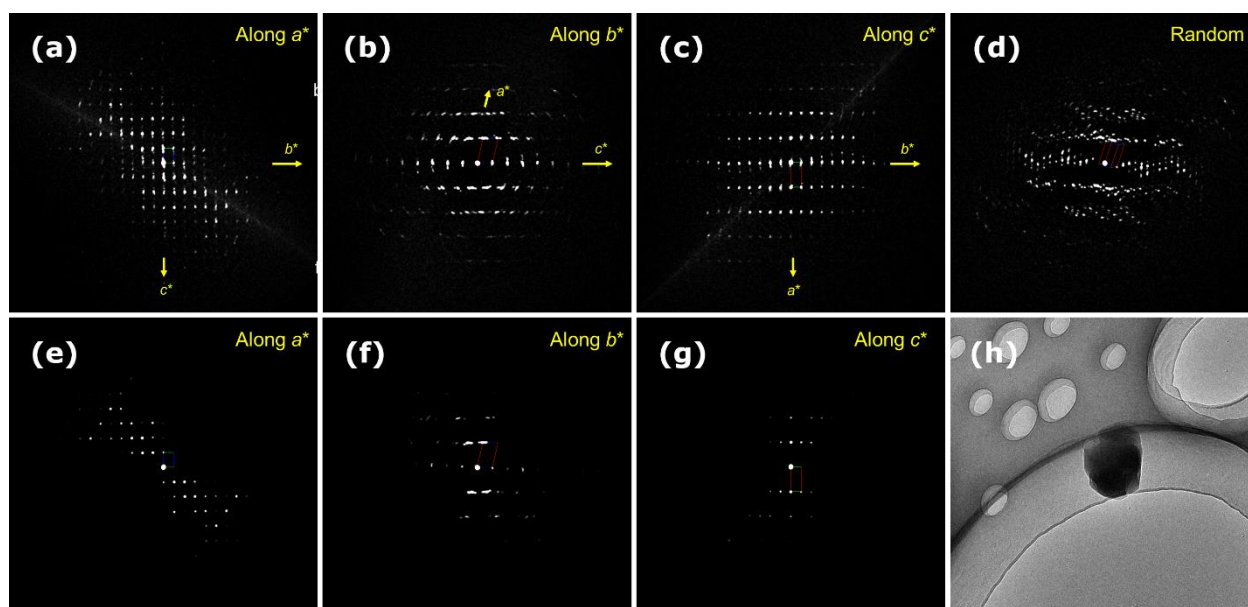


Fig. S8. (a – d) projection view of the 3D reciprocal lattice of Ga-TCPB, (e – g) 2D slices from the reconstructed 3D reciprocal lattice as obtained from the 3D ED data, and (h) low magnification bright-field image of the crystal.

Table S1. 3D crystallographic data and refinement details of V- and Ga-based MOFs.

	V-TBAPy	Ga-TBAPy	V-TCPB	Ga-TCPB
Composition	V ₂ O ₂ (TBAPy)	Ga ₂ (OH) ₂ (TBAPy)	V ₂ O ₂ (TCPB)	Ga ₂ (OH) ₂ (TCPB)
Crystal system	Monoclinic	Monoclinic	Orthorhombic	Monoclinic
Space group	<i>P2/m</i>	<i>P2/m</i>	<i>Pcma</i>	<i>P2/m</i>
<i>a</i> (Å)	6.760	6.698	6.496	6.504
<i>b</i> (Å)	15.696	15.321	15.835	15.971
<i>c</i> (Å)	15.638	16.095	21.590	10.970
α (°)	90	90	90	90
β (°)	103.4	102.8	90	103.4
γ (°)	90	90	90	90
Volume (Å ³)	1614.1	1610.6	2220.7	1108.5
D _c (g cm ⁻³)	0.813	0.854	1.029	1.060
Wavelength λ (Å)	0.02508 Å	0.02508 Å	0.02508 Å	0.02508 Å
Completeness (%)	89.81	89.95	81.62	67.41
Resolution (Å)	0.79 Å	0.90 Å	0.74 Å	0.75 Å
<i>R</i> _{int}	0.2861	0.2904	0.1464	0.0907
No. of symmetry independent reflections	3235	2082	2411	1940
<i>R</i> ₁	0.3540	-	0.2649	0.1798
<i>wR</i> ₂	0.6919	-	0.5788	0.5143
<i>Goof</i>	2.135	-	1.963	1.373

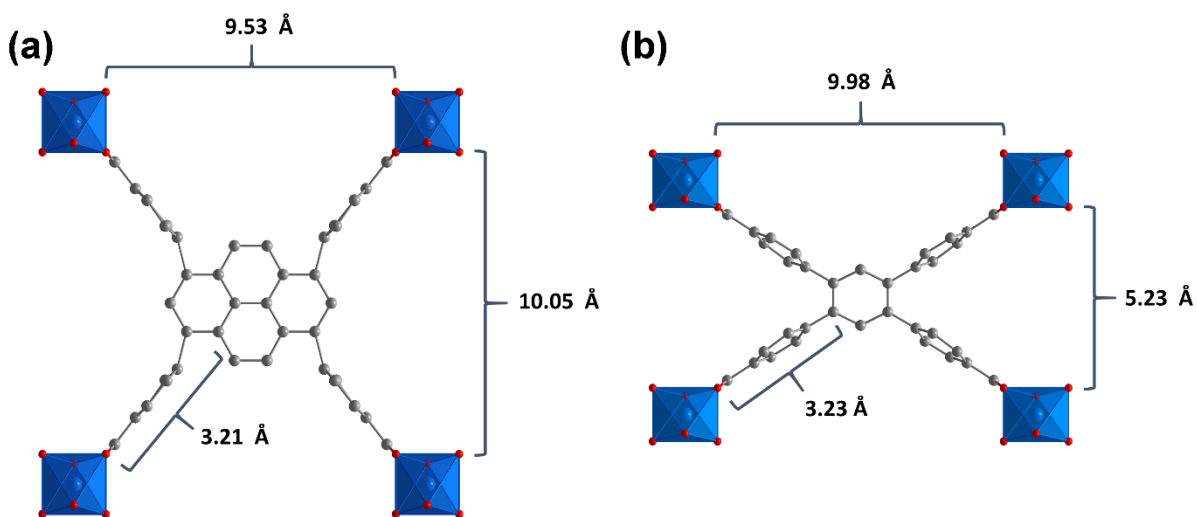


Fig. S9. Summary of dimensional differences between TBAPy- and TCPB-linkers in Ga-TBAPy and Ga-TCPB.

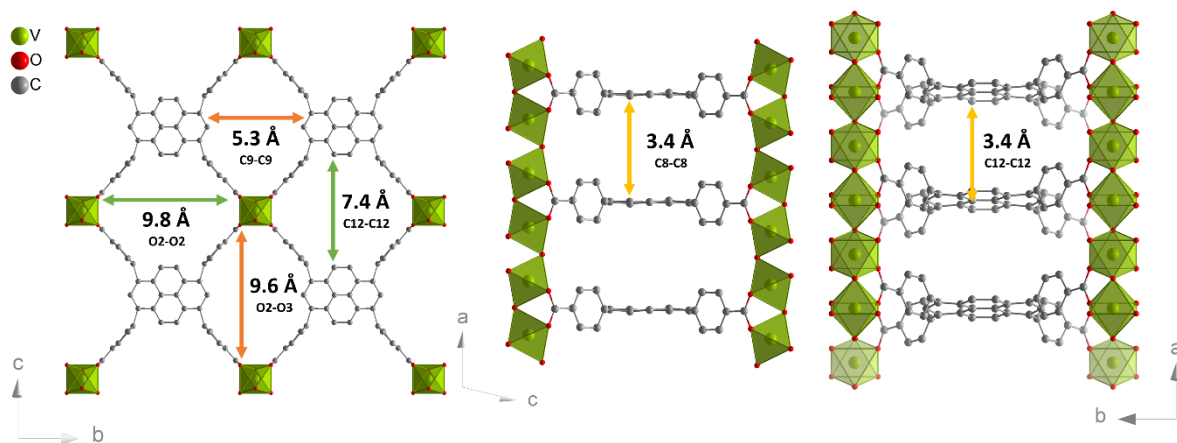
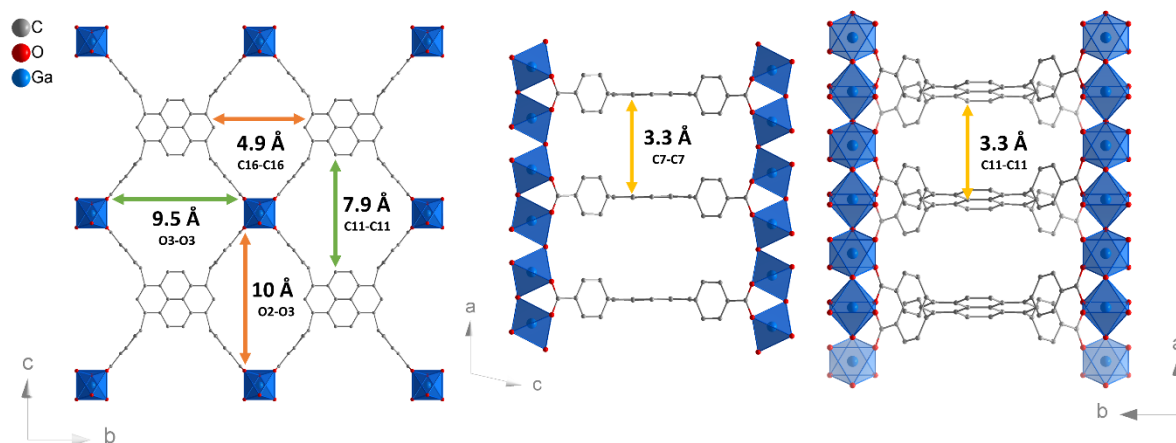


Fig. S10. Crystal structure of V-TBAPy as viewed along [001], [010], and [001] along with estimated pore diameters obtained by taking the van der Waals radii of the atoms into account.



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Fig. S11. Crystal structure of Ga-TBAPy as viewed along [001], [010], and [001] along with estimated pore diameters obtained by taking the van der Waals radii of the atoms into account.

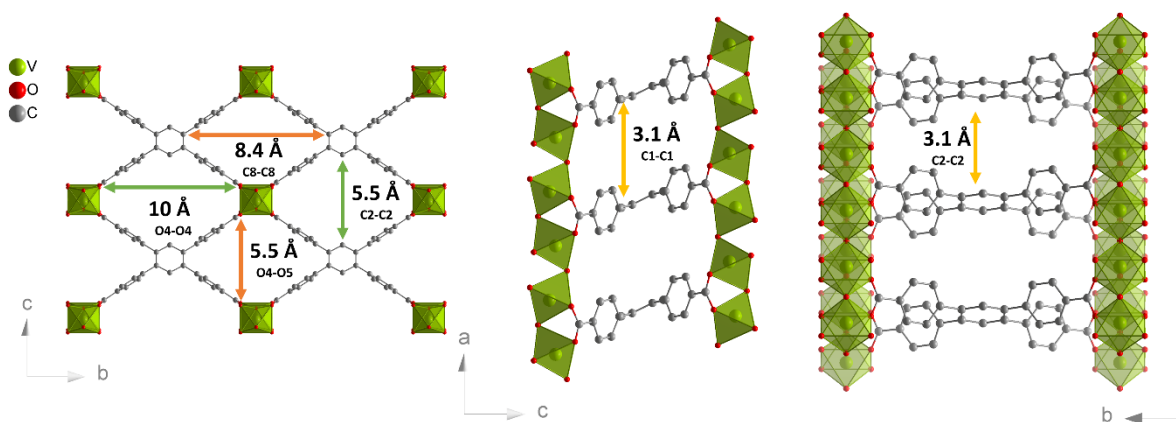


Fig. S12. Crystal structure of Ga-TCPB as viewed along [001], [010], and [001] along with estimated pore diameters obtained by taking the van der Waals radii of the atoms into account.

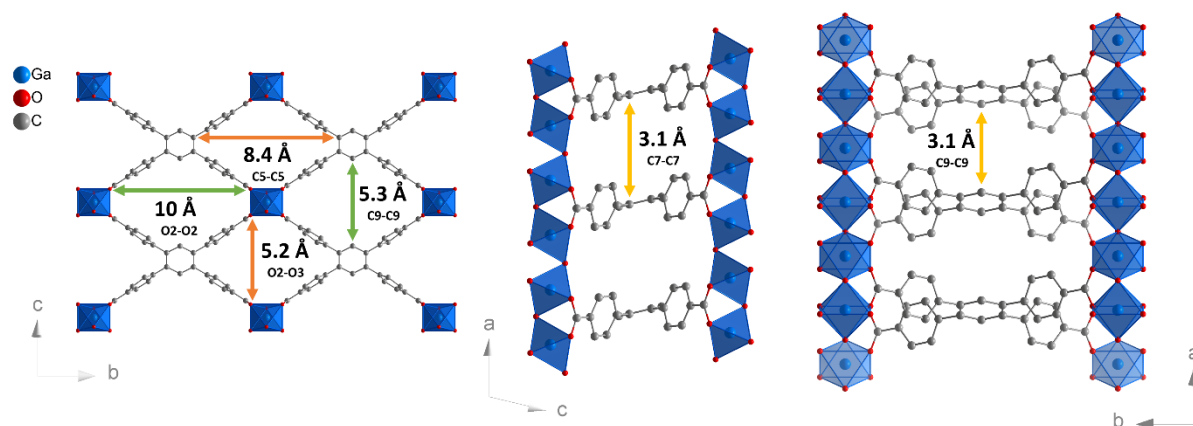


Fig. S13. Crystal structure of V-TCPB as viewed along [001], [010], and [001] along with estimated pore diameters obtained by taking the van der Waals radii of the atoms into account.

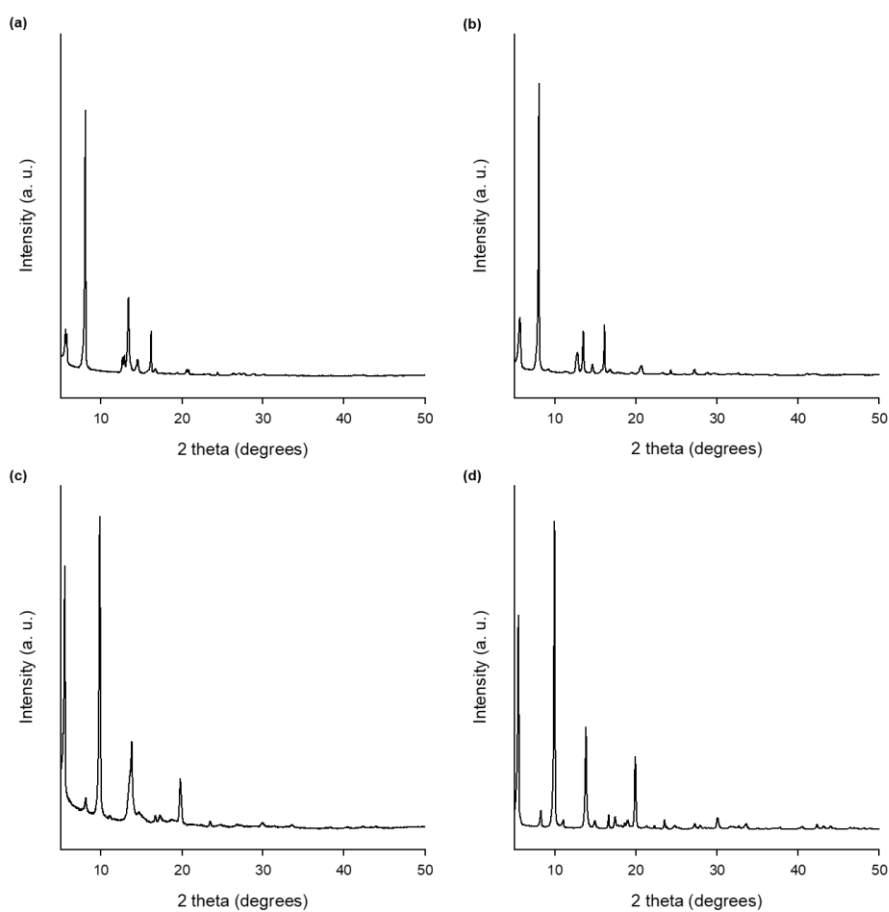


Fig. S14. Powder X-ray diffraction ($\lambda = 1.5418 \text{ \AA}$) patterns of (a) V-TBAPy, (b) Ga-TBAPy, (c) V-TCPB, and (d) Ga-TCPB.

Table S2. Atomic parameters obtained from Rietveld refinement of V-TBAPy^a.

Atom	Occupancy	x	y	z	U_{iso} (Å ²)
V1	1.0	0	0	0.5	0.024 (2) ^b
V2	1.0	0.5	0	0.5	0.024 (2) ^b
O1	1.0	0.781 (8)	0	0.556 (7)	0.02 (1) ^b
O2	1.0	0.890 (4)	0.894 (6)	0.433 (5)	0.02 (1) ^b
O3	1.0	0.610 (4)	0.923 (8)	0.403 (9)	0.02 (1) ^b
C1	1.0	0.740 (3)	0.842 (3)	0.393 (4)	0.011 (7) ^b
C2	1.0	0.768 (6)	0.7915 (13)	0.3151 (13)	0.011 (7) ^b
C3	1.0	0.758 (4)	0.8318 (13)	0.237 (2)	0.011 (7) ^b
C4	1.0	0.587 (4)	0.8182 (13)	0.165 (3)	0.011 (7) ^b
C5	1.0	0.539 (8)	0.7265 (13)	0.1600 (14)	0.011 (7) ^b
C6	1.0	0.557 (7)	0.6824 (16)	0.241 (2)	0.011 (7) ^b
C7	1.0	0.671 (11)	0.717 (2)	0.3173 (12)	0.011 (7) ^b
C8	1.0	0.550 (5)	0.6807 (9)	0.0826 (9)	0.011 (7) ^b
C9	1.0	0.5	0.722 (3)	0	0.011 (7) ^b
C10	1.0	0.5	0.5442 (15)	0.5	0.011 (7) ^b
C11	1.0	0.542 (12)	0.5900 (6)	0.0822 (7)	0.011 (7) ^b
C12	1.0	0.570 (4)	0.546 (2)	0.1608 (19)	0.011 (7) ^b

^aThe chemical composition of V-TBAPy for refinement is V₂O₂(C₄₄O₈). Lattice constants are $a = 6.754(7)$ Å, $b = 15.71(3)$ Å, $c = 15.66(3)$ Å, $\alpha = \gamma = 90^\circ$, $\beta = 103.2(2)^\circ$, resulting in $V = 1619(5)$ Å³. Agreement indices are $GoF = 2.66$, $R_{wp} = 8.94$. ^bAtomic displacement parameters (U_{iso}) of vanadium, oxygen, and carbon atoms in the framework are refined as a single parameter of each element.

Table S3. Atomic parameters obtained from Rietveld refinement of Ga-TBAPy^a.

Atom	Occupancy	x	y	z	U_{iso} (Å ²)
V1	1.0	0	0	0.5	0.005 (4) ^b
V2	1.0	0.5	0	0.5	0.005 (4) ^b
O1	1.0	0.778 (7)	0	0.556 (7)	0.031 (2) ^b
O2	1.0	0.890 (4)	0.895 (11)	0.420 (7)	0.031 (2) ^b
O3	1.0	0.530 (4)	0.911 (8)	0.403 (9)	0.031 (2) ^b
C1	1.0	0.701 (6)	0.857 (4)	0.375 (3)	0.027 (7) ^b
C2	1.0	0.699 (3)	0.8121 (14)	0.2978 (11)	0.027 (7) ^b
C3	1.0	0.894 (2)	0.762 (2)	0.194 (2)	0.027 (7) ^b
C4	1.0	0.587 (4)	0.8182 (13)	0.165 (3)	0.027 (7) ^b
C5	1.0	0.705 (5)	0.7244 (12)	0.1468 (13)	0.027 (7) ^b
C6	1.0	0.550 (3)	0.7083 (17)	0.194 (2)	0.027 (7) ^b
C7	1.0	0.549 (3)	0.754 (3)	0.2687 (14)	0.027 (7) ^b
C8	1.0	0.567 (3)	0.6829 (8)	0.0788 (8)	0.027 (7) ^b
C9	1.0	0.5	0.728 (4)	0	0.027 (7) ^b
C10	1.0	0.5	0.5452 (12)	0.5	0.027 (7) ^b
C11	1.0	0.543 (5)	0.5914 (5)	0.0787 (6)	0.027 (7) ^b
C12	1.0	0.567 (16)	0.543)	0.1558 (15)	0.027 (7) ^b

^aThe chemical composition of Ga-TBAPy for refinement is Ga₂O₂(C₄₄O₈). Lattice constants are $a = 6.697(5)$ Å, $b = 15.366(17)$ Å, $c = 16.01(2)$ Å, $\alpha = \gamma = 90^\circ$, $\beta = 101.5(1)^\circ$, resulting in $V = 1615(3)$ Å³. Agreement indices are $GoF = 3.38$, $R_{wp} = 9.43$. ^bThe atomic displacement parameters (U_{iso}) of gallium, oxygen, and carbon atoms in the framework are refined as a single parameter of each element.

Table S4. Atomic parameters obtained from Rietveld refinement of V-TCPB^a.

Atom	Occupancy	x	y	z	U_{iso} (Å ²)
V1	1.0	0.310 (3)	0	0.743 (6)	0.08 (7)
O1	1.0	0.310 (2)	0.907 (17)	0.809 (9)	0.02 (8) ^b
O2	1.0	0.550 (5)	0	0.810 (3)	0.02 (8) ^b
O3	1.0	0.020 (5)	0.930 (2)	0.800 (11)	0.02 (8) ^b
C1	1.0	0.137 (4)	0.890 (3)	0.846 (4)	0.020 (13) ^b
C2	1.0	0.097 (3)	0.8097 (15)	0.871 (3)	0.020 (13) ^b
C3	1.0	0.020 (3)	0.6536 (11)	0.9270 (16)	0.020 (13) ^b
C4	1.0	0.252 (2)	0.757 (3)	0.890 (5)	0.020 (13) ^b
C5	1.0	0.213 (3)	0.6777 (15)	0.915 (3)	0.020 (13) ^b
C6	1.0	-0.093 (3)	0.7902 (18)	0.892 (4)	0.020 (13) ^b
C7	1.0	-0.132 (3)	0.711 (2)	0.918 (4)	0.020 (13) ^b
C8	1.0	-0.019 (5)	0.583 (2)	0.9649 (13)	0.020 (13) ^b
C9	1.0	0	0.5	0.941 (2)	0.020 (13) ^b

^aThe chemical composition of V-TCPB for refinement is $V_2O_2(C_{34}O_8)$. Lattice constants are $a = 6.822(13)$ Å, $b = 15.84(5)$ Å, $c = 21.59(3)$ Å, $\alpha = \beta = \gamma = 90^\circ$, resulting in $V = 2333(9)$ Å³. Agreement indices are $GoF = 2.14$, $R_{wp} = 7.64$. ^bThe atomic displacement parameters (U_{iso}) of vanadium, oxygen, and carbon atoms in the framework are refined as a single parameter of each element.

Table S5. Atomic parameters obtained from Rietveld refinement of Ga-TCPB^a.

Atom	Occupancy	x	y	z	U_{iso} (Å ²) ^b
Ga1	1.0	0	0	0.5	0.006 (4) ^b
Ga2	1.0	0.5	0	0.5	0.006 (2) ^b
O1	1.0	0.781 (2)	0	-0.390 (3)	0.02 (1) ^b
O2	1.0	0.120 (4)	-0.082 (6)	-0.366 (3)	0.02 (1) ^b
O3	1.0	0.460 (2)	-0.093 (9)	-0.389 (9)	0.02 (1) ^b
C1	1.0	0.326 (3)	-0.120 (3)	-0.328 (5)	0.004 (5) ^b
C2	1.0	0.3763 (19)	-0.1911 (11)	-0.254 (2)	0.004 (5) ^b
C3	1.0	0.219 (2)	-0.2320 (13)	-0.216 (3)	0.004 (5) ^b
C4	1.0	0.573 (2)	-0.2302 (13)	-0.234 (3)	0.004 (5) ^b
C5	1.0	0.606 (2)	-0.3109 (12)	-0.184 (3)	0.004 (5) ^b
C6	1.0	0.255 (2)	-0.3128 (12)	-0.166 (2)	0.004 (5) ^b
C7	1.0	0.4529 (18)	-0.3491 (8)	-0.1415 (16)	0.004 (5) ^b
C8	1.0	0.501 (3)	-0.4233 (18)	-0.069 (2)	0.004 (5) ^b
C9	1.0	0.415(18)	0.5	-0.122(4)	0.04) ^b

^aThe chemical composition of Ga-TCPB for refinement is Ga₂O₂(C₃₄O₈). Lattice constants are $a = 6.695(5)$ Å, $b = 16.05(2)$ Å, $c = 11.228(10)$ Å, $\alpha = \gamma = 90^\circ$, $\beta = 107.84(11)^\circ$, resulting in $V = 1149(2)$ Å³. Agreement indices are $GoF = 3.27$, $R_{wp} = 9.59$. ^b The atomic displacement parameters (U_{iso}) of gallium, oxygen, and carbon atoms in the framework are refined as a single parameter of each element.

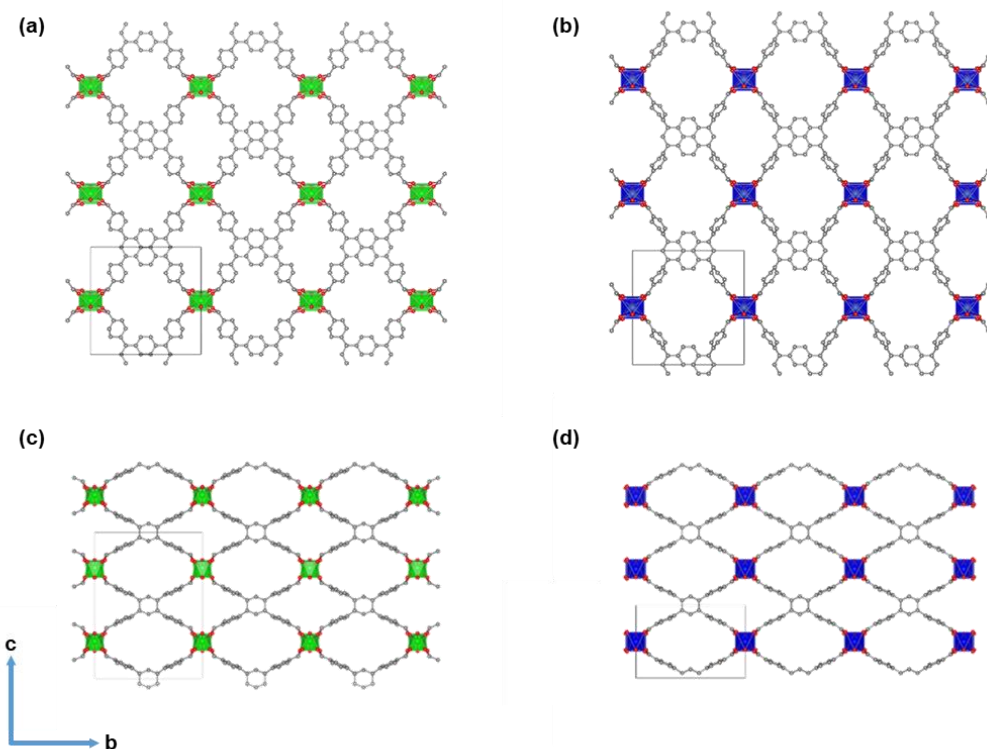


Fig. S15. Atomic configuration of (a) V-TBAPy, (b) Ga-TBAPy, (c) V-TCPB, and (d) Ga-TCPB along [100], drawn based on the crystal structure as determined by Rietveld refinement: V and VO₆ unit (green), Ga and GaO₆ unit (blue), O (red), and C (grey).

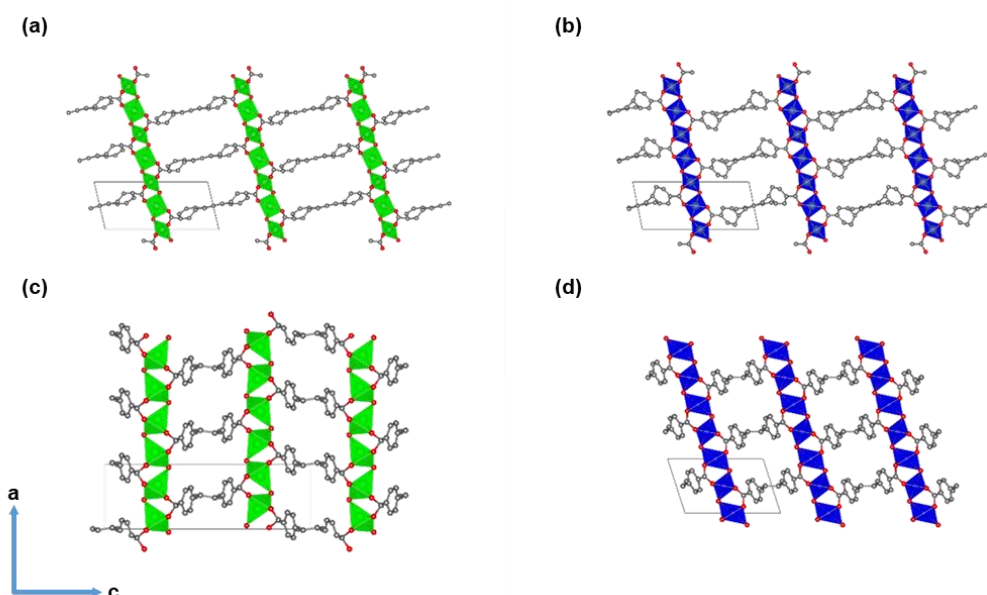


Fig. S16. Atomic configuration of (a) V-TBAPy, (b) Ga-TBAPy, (c) V-TCPB, and (d) Ga-TCPB along [010], drawn based on the crystal structure as determined by Rietveld refinement: V and VO₆ unit (green), Ga and GaO₆ unit (blue), O (red), and C (grey).

Section S3. X-ray photoelectron spectroscopy

Survey and high-resolution core-level X-ray photoelectron spectroscopy (XPS) spectra were recorded on an Ulvac-PHI Quantera II XPS Scanning Microprobe using monochromatic Al K α as an X-ray source. All measurements were conducted under a constant exposure of low-energy electrons and argon ions in order to avoid charge build-up. Both the core-level spectra of V2p could be deconvoluted as two single-component peaks, indicating that the MOFs contain a single vanadium species. Furthermore, binding energies for V2p_{3/2} and V2p_{1/2} (Table S6) was measured to be 515.78 eV, 523.13 eV and 515.95 eV, 523.30 eV for V-TBAPy and V-TCPB, respectively, and a difference in binding energy between O1s and V2p_{3/2} was calculated to be 14.60 and 14.61, indicating that the oxidation state of vanadium in both MOFs is V(IV)^{10, 11}.

The presence of Si in the survey spectra comes from the substrates (silicon wafers) that the MOFs were placed on during the measurements.

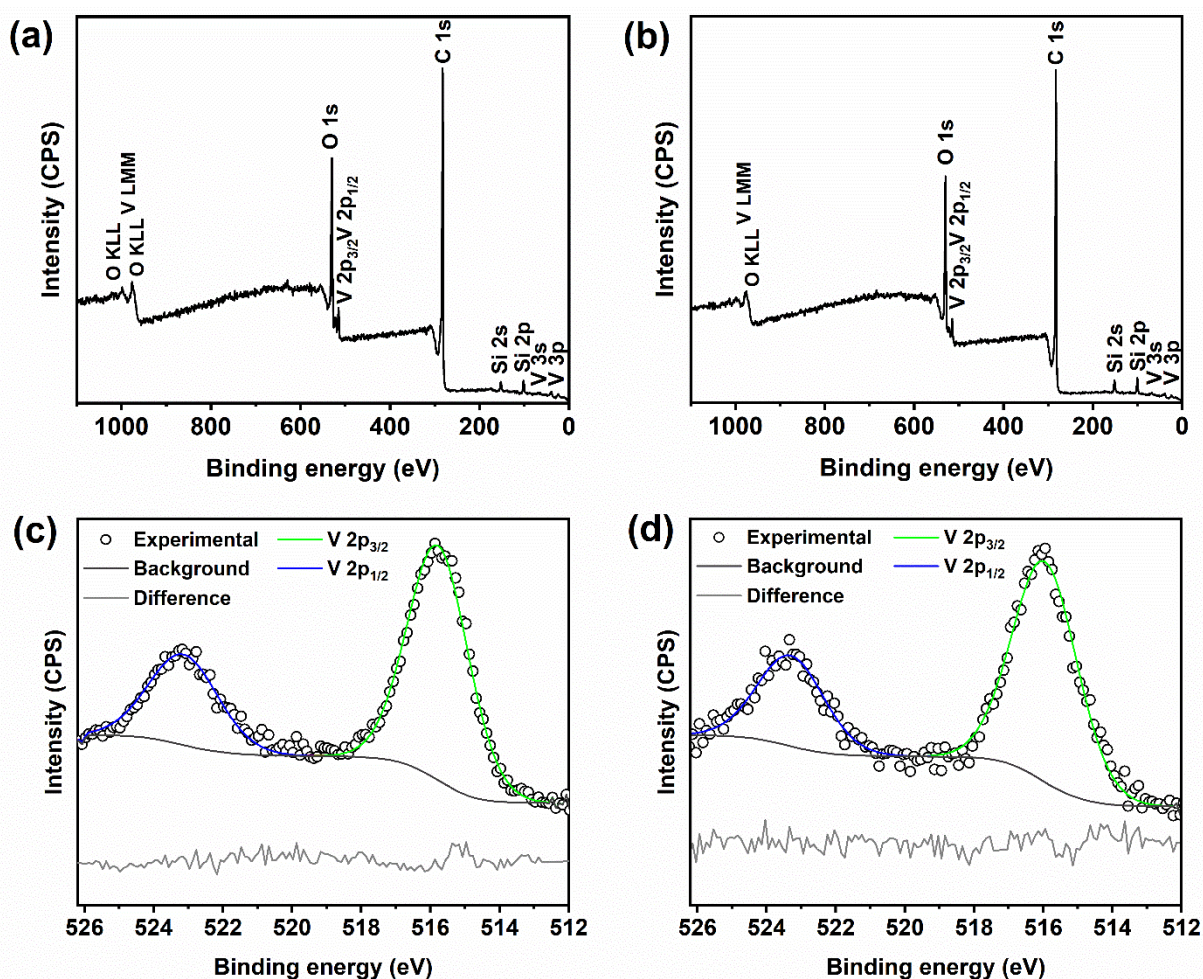


Fig. S17. XPS (a – b) survey and core-level (c – d) spectra of (a)/(c) V-TBAPy and (b)/(d) V-TCPB.

Table S6. Summary of V2p and O1s peak fit parameters for V-TBAPy and V-TCPB.

Sample	V-TBAPy	V-TCPB
Binding energy (eV)		
V2p _{3/2}	515.78	515.95
V2p _{1/2}	523.13	523.30
O1s	530.38	530.50
Δ (V2p _{1/2} and V2p _{3/2})	7.35	7.35
Δ (O1s and V2p _{3/2})	14.60	14.61

Section S4. Stability study

The chemical stability of the as-synthesized MOFs was evaluated by soaking 8 mg of each material in 5 ml of the following solutions; 1 M HCl, deionized water, 1 M NaOH, MeOH, EtOH, toluene, and acetone, for 24 h whilst stirring at 300 rpm. The materials were thereafter collected by centrifugation at 3,800 rpm for 10 min and analyzed using PXRD, Figure S17 – S18. All samples can be observed to have low stability in strongly acidic or basic solutions after 24 h. The frameworks can be seen to either partially decompose or fully dissolve after having been left stirring in these solutions, indicating that the coordination between the metal ions and organic linkers may be vulnerable to gradual replacement in these conditions. The structural stability of MOFs in all other solutions and solvents was found to be high, with only minor changes in crystallinity possibly connected to the adsorption of molecules into the frameworks. The thermal stability of MOFs was studied in air (60 ml min⁻¹ flow-rate) using thermogravimetric analysis (TGA), Figure S19. All samples were found to remain stable up to 350 °C, with the Ga-based MOFs showing significantly higher thermal stability (decomposing at approx. 450 °C).

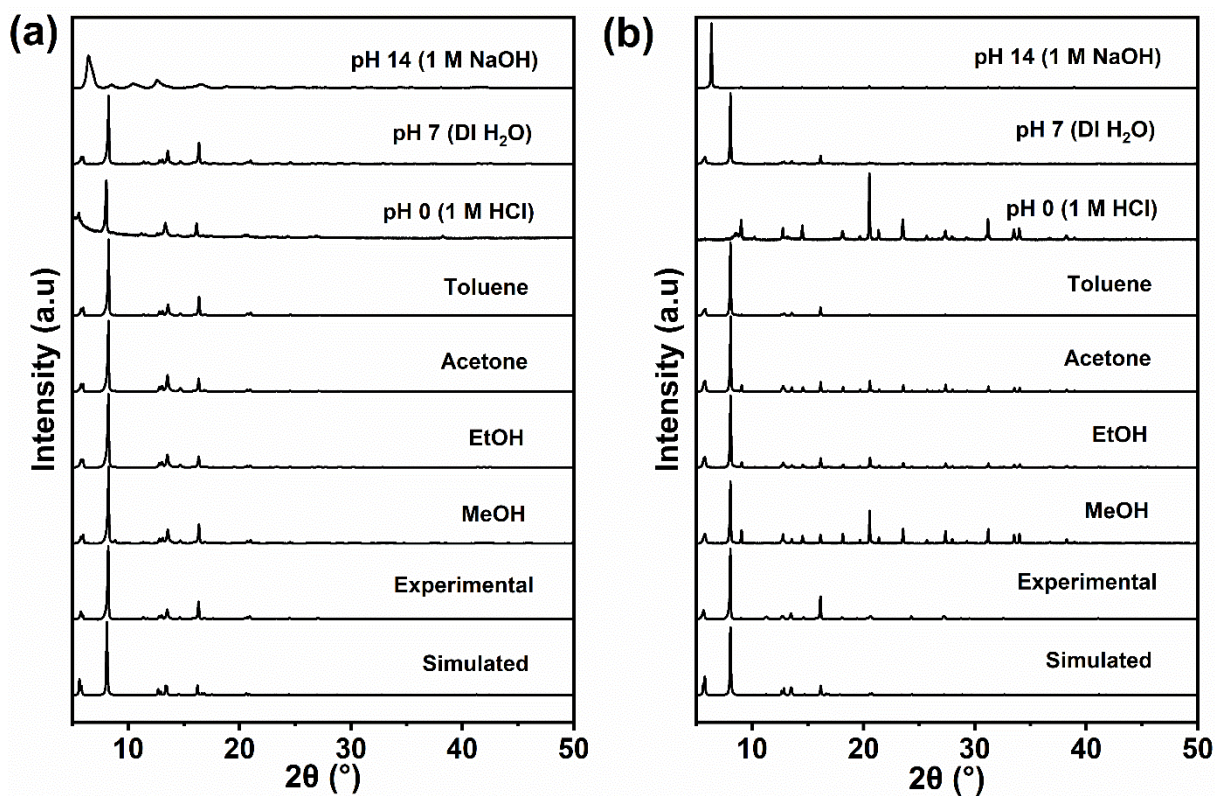


Fig. S18. X-ray powder diffractograms of (a) V-TBAPy and (b) Ga-TBAPy

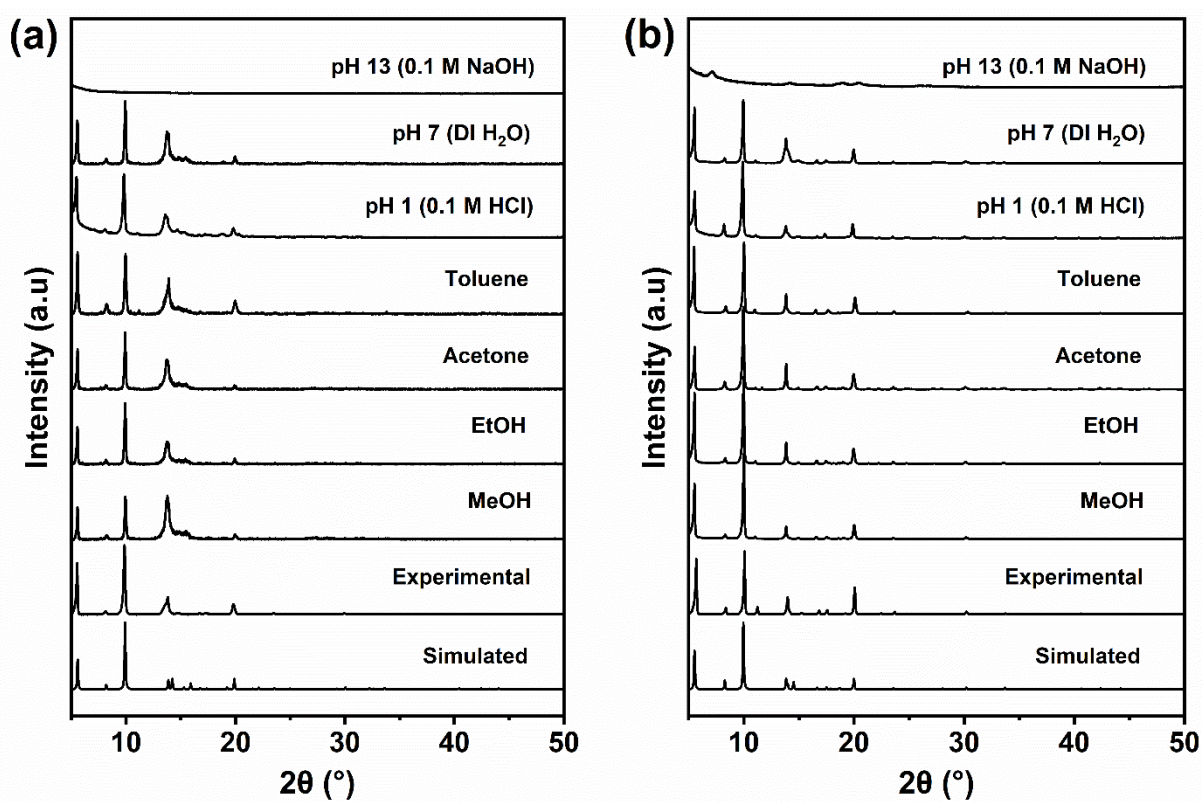


Fig. S19. X-ray powder diffractograms of (a) V-TCPB and (b) Ga-TCPB

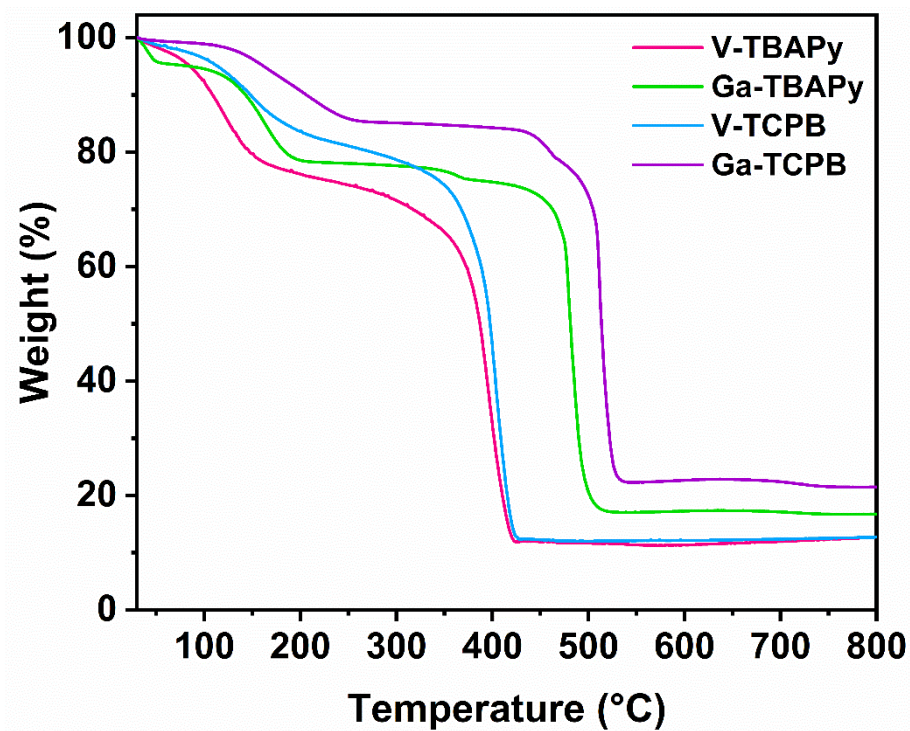


Fig. S20. Thermogravimetric decomposition profiles of Ga- and V-based MOFs.

Section S5. Scanning electron microscopy images

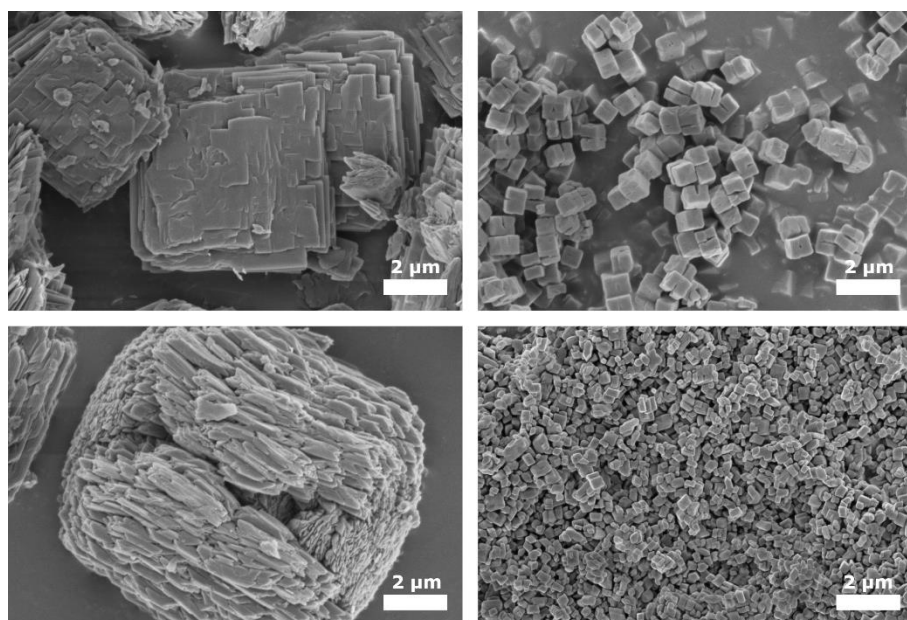


Fig. S21. Scanning electron microscopy images of (a) V-TBAPy, (b) Ga-TBAPy, (c) V-TCPB, and (d) Ga-TCPB.

Section S6. Porosity and gas sorption

Gas sorption experiments were performed using a Micromeritics ASAP 2020 surface area analyzer (Norcross, GA, USA). All samples were pre-treated at 423 K for 3 h under a dynamic vacuum (1×10^{-4} Pa) prior to analysis. Brunauer-Emette-Teller (BET) and Langmuir-specific surface areas were calculated from N_2 adsorption isotherms recorded at 77 K. Pore size distributions were estimated using the Density Functional Theory (DFT) function in the Micromeritics MicroActive software using the N_2 adsorption isotherms, the slit pore model for N_2 was used for these calculations. SF_6 , CO_2 , CH_4 , and N_2 sorption isotherms at 283 - 303 K were also recorded using the Micromeritics ASAP 2020 surface area analyzer with an insulating water bath. Gravimetric gas adsorption profiles were obtained using a Mettler Toledo TGA/DSC 3+ (Schwerzenbach, Switzerland) using N_2 as purge gas and SF_6 or CO_2 as measurement gas. All experiments were carried out on approx. 10 mg of material degassed at 423 K for 30 min in a N_2 atmosphere (50 ml min^{-1} flow-rate) before the sample were subjected to SF_6 or CO_2 at 303 K for up to 30 min (50 ml min^{-1} flow-rate). Temperature-swing adsorption experiments were carried out under the same conditions, however using a shorter degas time of 12 min in-between each cycle.

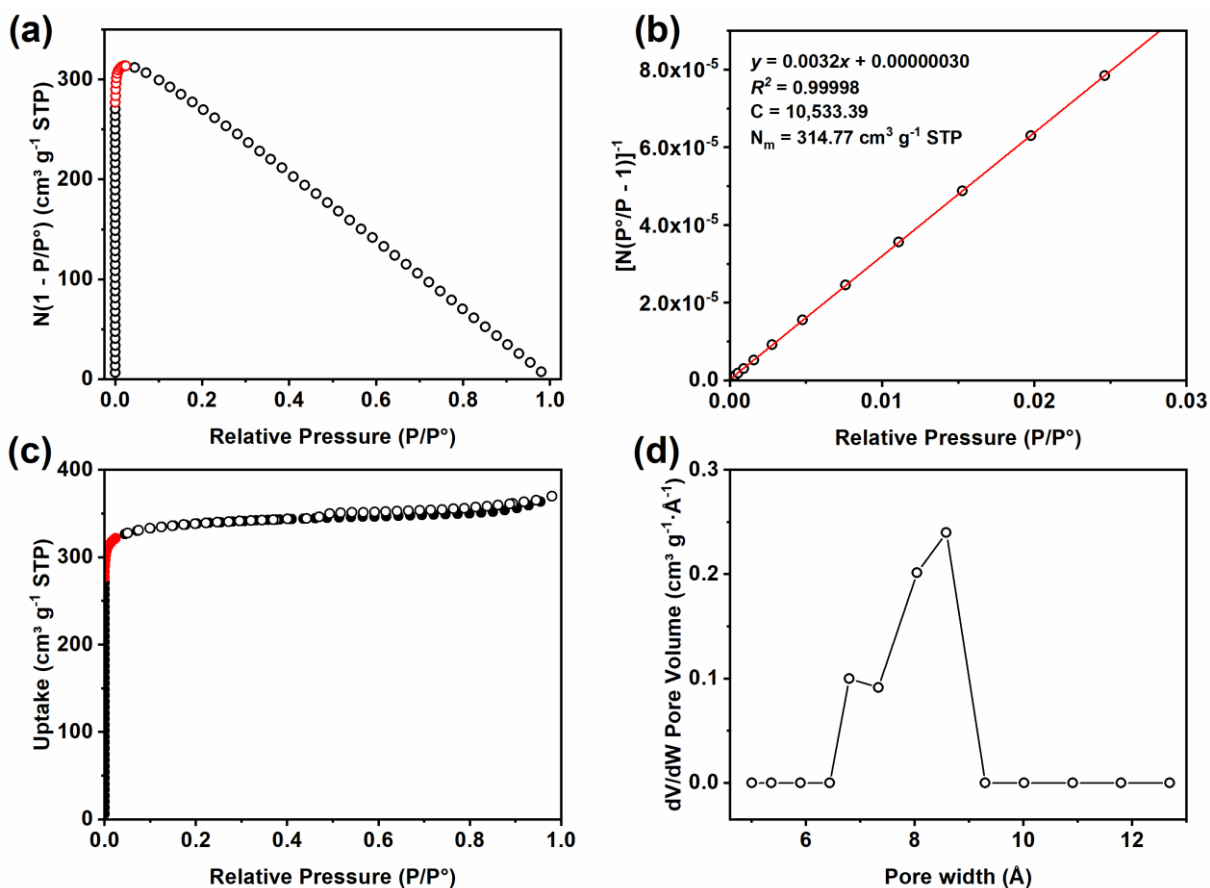


Fig. S22. (a) Rouquerol plot, (b) BET surface area plot showing selected points for satisfying the Rouquerol criterion, (c) N_2 sorption isotherm recorded at 77 K, and (d) corresponding density-functional theory pore size distributions for V-TBAPy. Red hollow and solid spheres correspond to selected points used for calculating the BET surface area of the material. Black-filled and hollow spheres denote the adsorption and desorption branches of the N_2 isotherm, respectively.

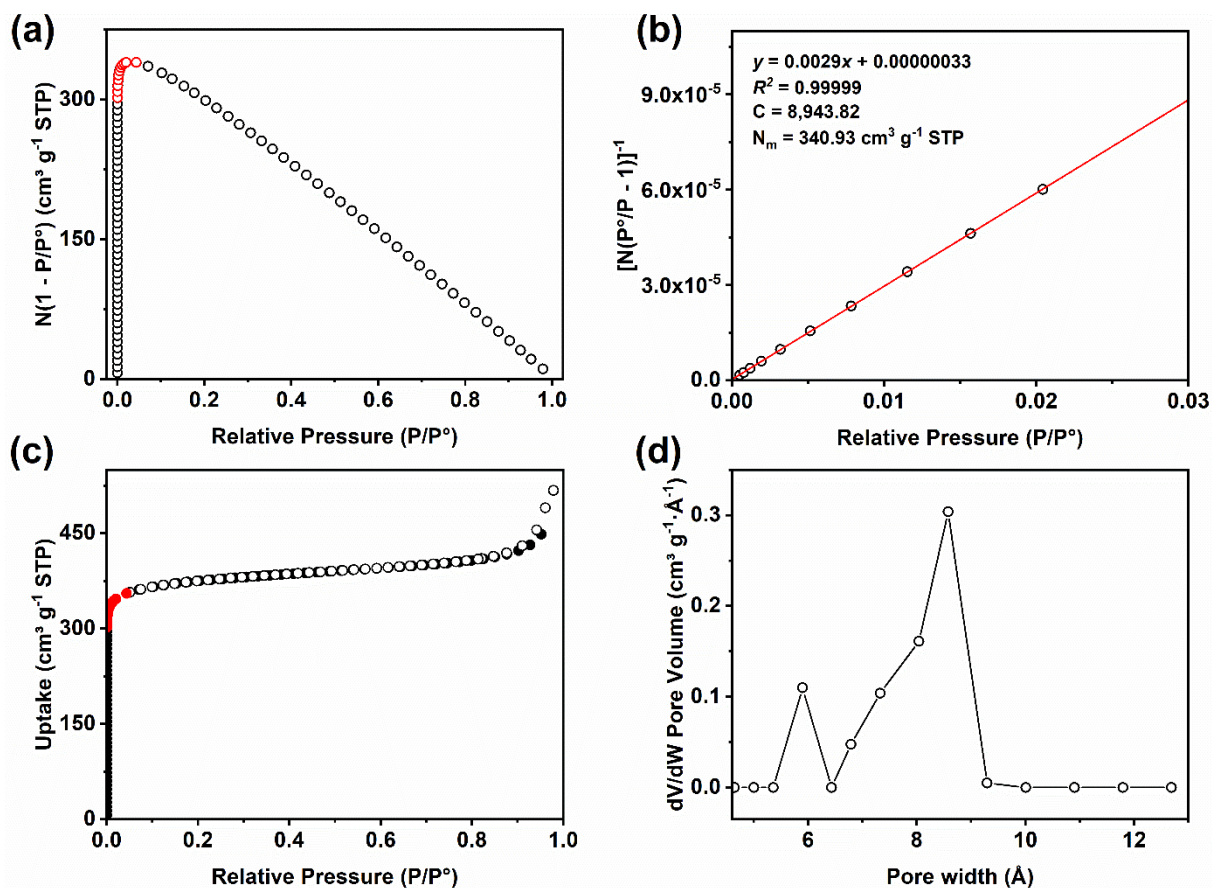


Fig. S23. (a) Rouquerol plot, (b) BET surface area plot showing selected points for satisfying the Rouquerol criterion, (c) N_2 sorption isotherm recorded at 77 K, and (d) corresponding density-functional theory pore size distributions for Ga-TBAPy. Red hollow and solid spheres correspond to selected points used for calculating the BET surface area of the material. Black-filled and hollow spheres denote the adsorption and desorption branches of the N_2 isotherm, respectively.

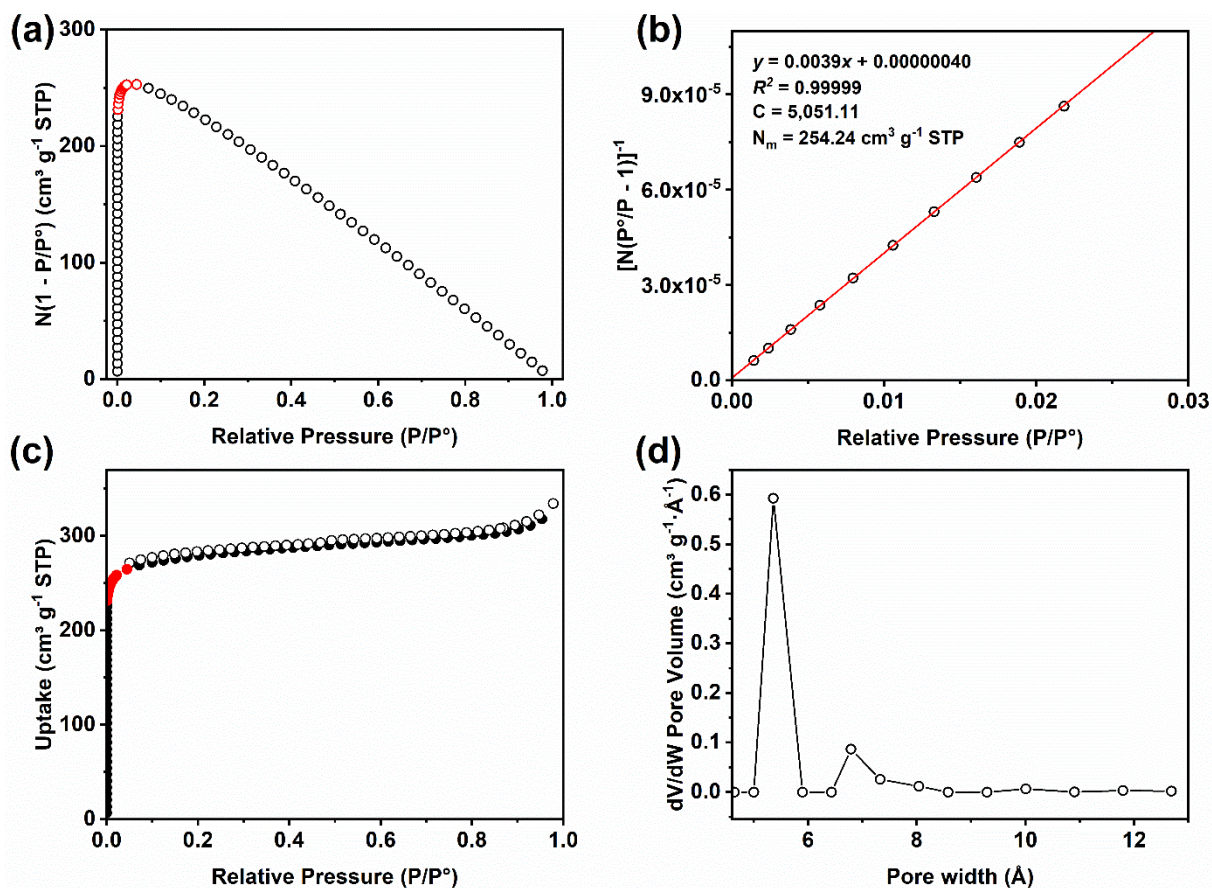


Fig. S24. (a) Rouquerol plot, (b) BET surface area plot showing selected points for satisfying the Rouquerol criterion, (c) N₂ sorption isotherm recorded at 77 K, and (d) corresponding density-functional theory pore size distributions for V-TCPB. Red hollow and solid spheres correspond to selected points used for calculating the BET surface area of the material. Black-filled and hollow spheres denote the adsorption and desorption branches of the N₂ isotherm, respectively.

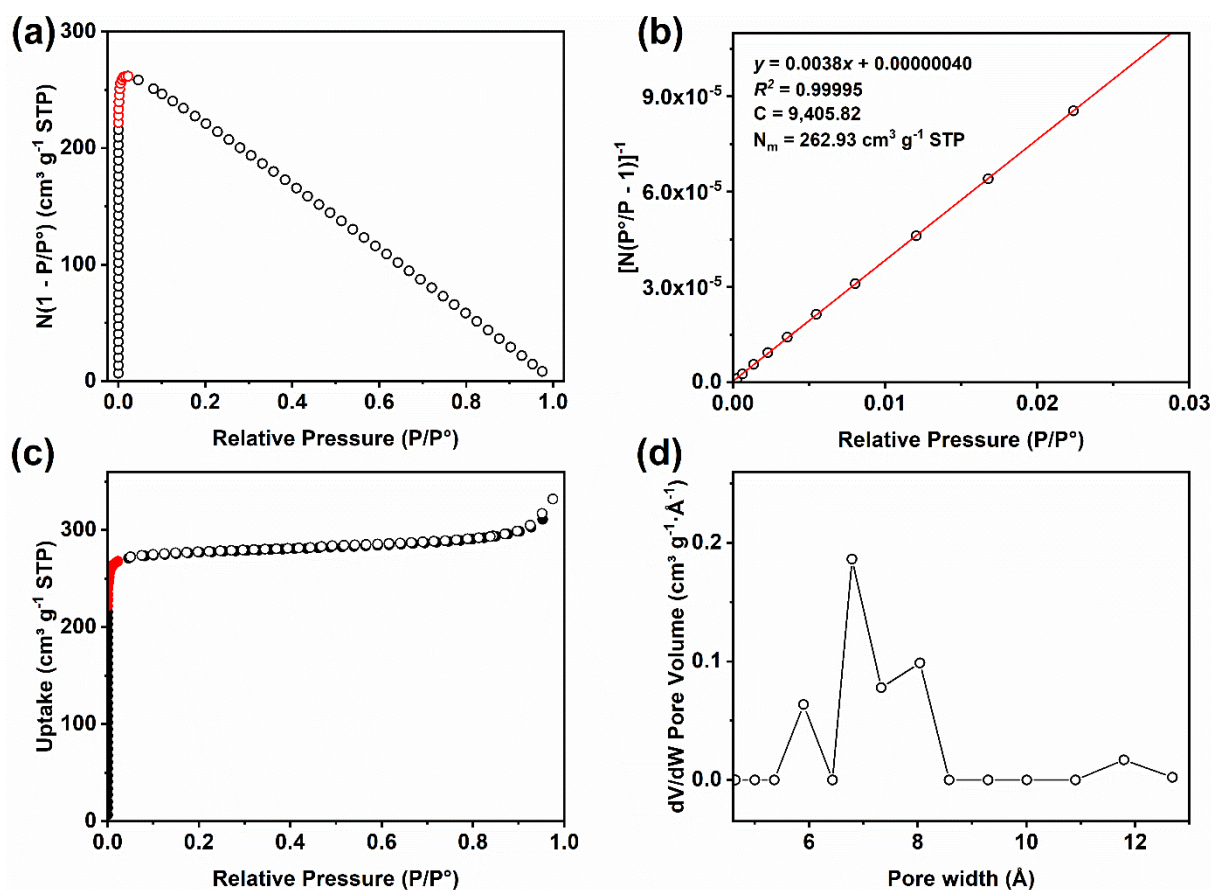


Fig. S25. (a) Rouquerol plot, (b) BET surface area plot showing selected points for satisfying the Rouquerol criterion, (c) N_2 sorption isotherm recorded at 77 K, and (d) corresponding density-functional theory pore size distributions for Ga-TCPB. Red hollow and solid spheres correspond to selected points used for calculating the BET surface area of the material. Black-filled and hollow spheres denote the adsorption and desorption branches of the N_2 isotherm, respectively.

Table S7. Summary of porosity properties of the V-TABPy, Ga-TBAPy, V-TCPB, and Ga-TCPB.

Sample	BET surface area ^a ($m^2 g^{-1}$)	Langmuir surface area ($m^2 g^{-1}$)	BET constant, C	Pore volume ^b ($cm^3 g^{-1}$)	Pore size ^c (\AA)
V-TBAPy	1370	1482	10,533.39	0.557	6.40, 8.60
Ga-TBAPy	1484	1646	8,943.82	0.669	5.90, 8.60
V-TCPB	1107	1224	5,051.11	0.482	5.38, 6.82
Ga-TCPB	1144	1209	9,405.82	0.469	5.95, 6.80, 7.85

^aCalculated from the N_2 adsorption isotherm recorded at 77 K in the P/P° -range given in Figs. S22-S25.

^bTotal pore volume estimated from the adsorption branch of the N_2 isotherm recorded at 77 K at $P/P^\circ = 0.93$.

^cCalculated by DFT from the adsorption branch of the N_2 isotherm recorded at 77 K at $P/P^\circ < 1 \times 10^{-2}$ using a slit-type pore geometry.

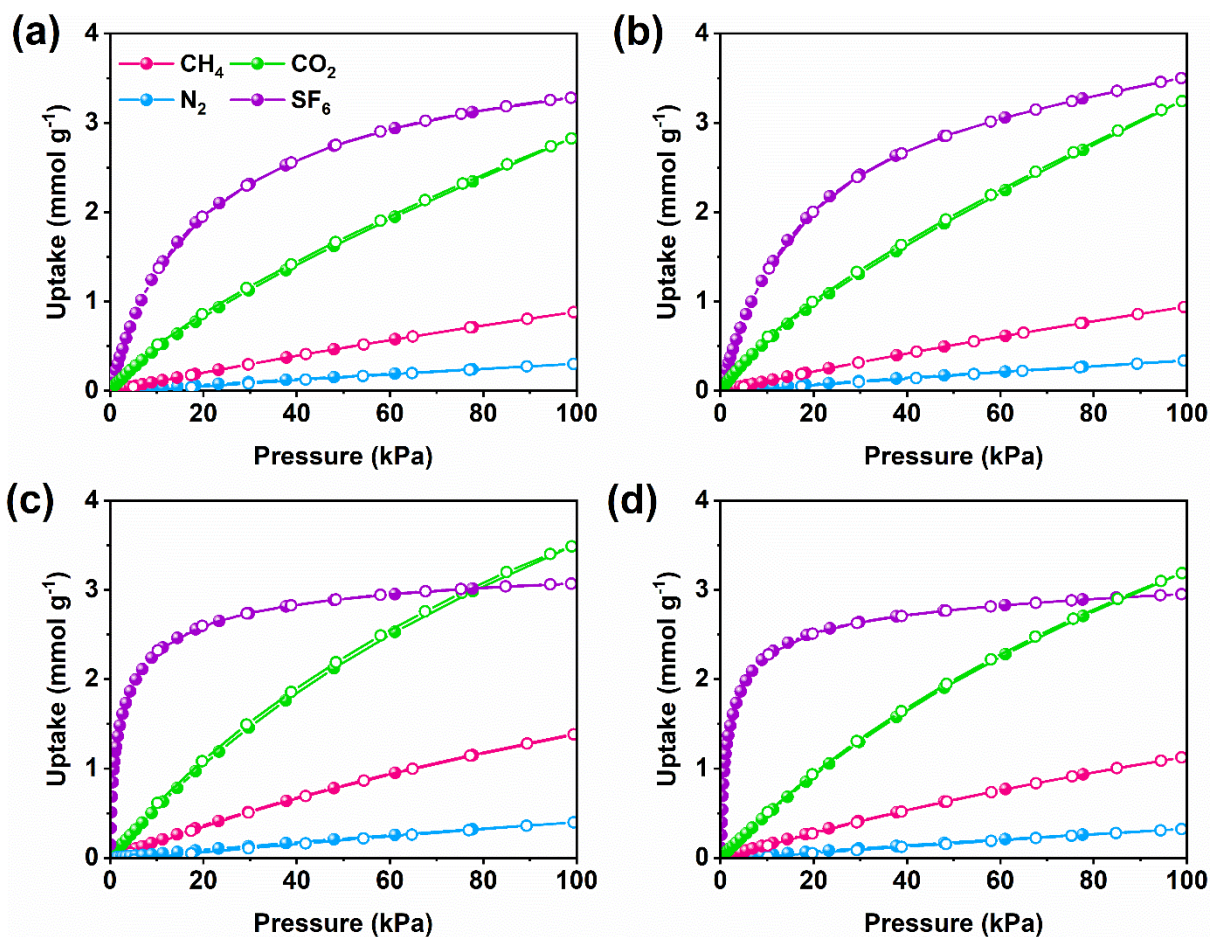


Fig. S26. CH₄, CO₂, N₂, and SF₆ sorption isotherms recorded at 293 K of (a) V-TBAPy, (b) Ga-TBAPy, (c) V-TCPB, and (d) Ga-TCPB. Filled and hollow spheres represent the adsorption and desorption isotherms, respectively.

Table S8. Uptake capacities of CH₄, CO₂, N₂, and SF₆ at 293 K and 100 kPa of V-TBAPy, Ga-TBAPy, V-TCPB, and Ga-TCPB.

Samples	CH ₄ (mmol g ⁻¹)	CO ₂ (mmol g ⁻¹)	N ₂ (mmol g ⁻¹)	SF ₆ (mmol g ⁻¹)
V-TBAPy	0.88	2.83	0.30	3.28 1.32 ^a
Ga-TBAPy	0.94	3.24	0.34	3.50 1.33 ^a
V-TCPB	1.38	3.49	0.40	3.07 2.29 ^a
Ga-TCPB	1.13	3.19	0.32	2.95 2.25 ^a

^aUptake at 10 kPa.

Table S9. Summary of SF₆ uptake capacities, selectivities, and enthalpies of adsorption of various MOF sorbents.

Materials	SF ₆ uptake at 10 kPa (mmol g ⁻¹)	SF ₆ uptake at 100 kPa (mmol g ⁻¹)	IAST selectivity (10:90) SF ₆ /N ₂	-ΔH _{ads} (kJ mol ⁻¹) ^a	Ref.
Cu-MOF-NH ₂	3.39	7.88	266.2	55.20	12
Zn(TMBDC)(DABCO) _{0.5}	2.48	4.61	219.0	45.20	13
Ni(ina) ₂	2.39	2.84	375.1	33.40	14
V-TCPB	2.29	3.07	360.7	30.48	This work
Ga-TCPB	2.26	2.95	418.5	30.44	This work
Ni(adc)(dabco) _{0.5}	2.23	2.38	919.4	47.68	15
Co-MOF-74	2.09	5.34	35.1	40.00	16
Mg-MOF-74	2.04	6.42	18.9	32.00	16
Ni(3-mpba) ₂	1.79	2.83	221.0	30.20	17
Co(3-mpba) ₂	1.77	3.25	161.0	26.80	17
Ni(pba) ₂	1.69	3.47	156.5	26.10	17
Zn-MOF-74	1.42	3.72	46.0	25.00	16
HKUST-1	1.41	6.71	159.4	27.73	18
Zn(DMBDC)(DABCO) _{0.5}	1.40	4.77	109.3	26.50	13
Ga-TBAPy	1.33	3.50	55.4	27.18	This work
V-TBAPy	1.33	3.28	65.6	28.08	This work
CAU-10-Py	1.13	1.76	203.6	32.60	19
SBMOF-1	0.93	1.02	325.0	32.50	20
UiO-66	0.82	1.67	129.9	32.38	21
UiO-66-Br ₂	0.76	0.94	222.2	44.62	21
CAU-10-H	0.68	1.00	122.6	24.90	19
UiO-67	0.48	3.58	21.5	20.43	22
MIL-100(Fe)	0.30	2.59	15.8	24.19	23

^aAt zero or low coverage

Section S6.1. Isothermic enthalpies of adsorption

Isothermic enthalpies of SF₆ and CO₂ adsorption were estimated from pure-component isotherms of SF₆ or CO₂ recorded at 283 – 303 K using the Virial equation (Eq. 1)²⁴:

$$\ln P = \ln N + \frac{1}{T} \sum_{i=0}^m a_i N^i + \sum_{j=0}^n b_j N^j \quad [1]$$

Where P (kPa) is the ideal gas constant, N (mmol g⁻¹) quantity of adsorbed gas at temperature T (K), a_i and b_j virial coefficients.

The isothermic enthalpy of adsorption (ΔH_{ads}) was thereafter calculated using Eq. 2:

$$\Delta H_{ads} = R \sum_{i=0}^m a_i N^i \quad [2]$$

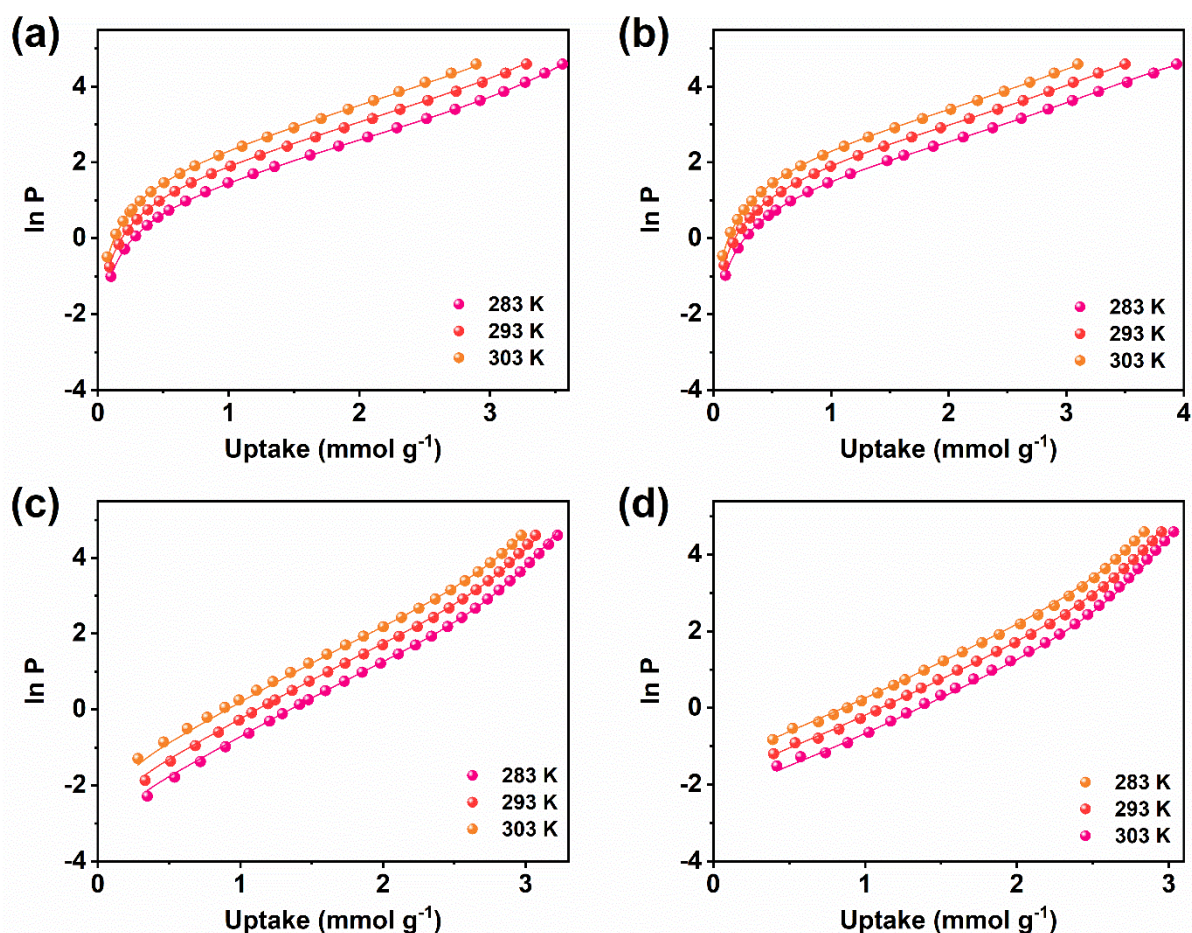


Fig S27. Virial fit of SF₆ adsorption isotherms recorded at 283 – 303 K for (a) V-TBAPy, (b) Ga-TBAPy, (c) V-TCPB, and (d) Ga-TCPB.

Table S10. Fitting parameters and virial coefficients obtained from SF₆ adsorption isotherms recorded at 283 – 303 K of V-TBAPy.

Sample	V-TBAPy ±	Ga-TBAPy	V-TCPB	Ga-TCPB
a_0	-3280.456	-3198.130	-3487.004	-3428.464
a_1	-392.009	-300.055	-909.842	-3428.464
a_2	13.265	76.659	757.361	972.760
a_3	33.483	-44.172	-305.211	-381.211
a_4	-14.937	15.391	47.576	61.515
a_5	2.208	-1.775	-	-
b_0	12.883	12.598	11.562	12.050
b_1	1.418	1.084	1.497	1.266
RMSE	0.01998	0.01455	0.05194	0.04840

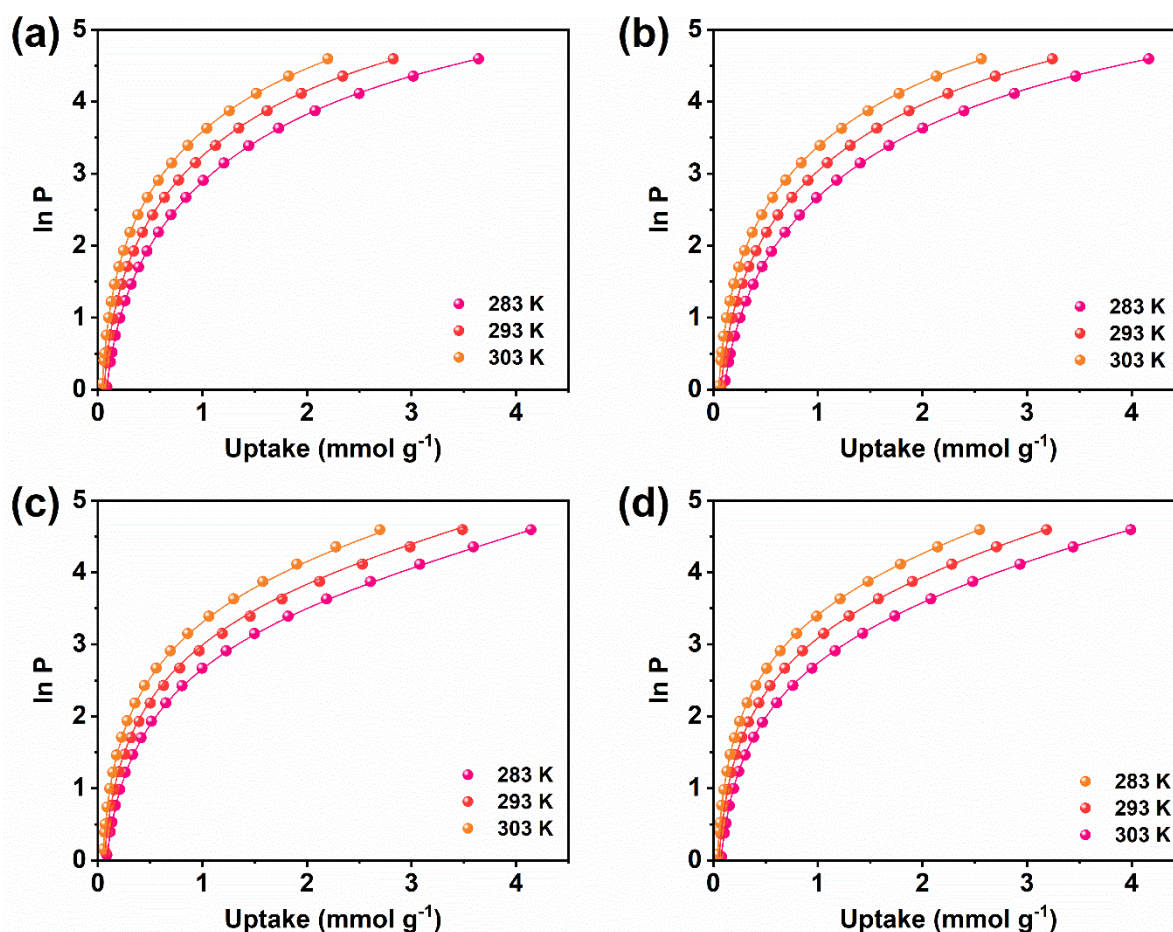


Fig S28. Virial fit of CO₂ adsorption isotherms recorded at 283 – 303 K for (a) V-TBAPy, (b) Ga-TBAPy, (c) V-TCPB, and (d) Ga-TCPB.

Table S11. Fitting parameters and virial coefficients obtained from CO₂ adsorption isotherms recorded at 283 – 303 K of V-TBAPy.

Sample	V-TBAPy	Ga-TBAPy	V-TCPB	Ga-TCPB
a_0	-3346.979	-3304.601	-2767.651	-2800.397
a_1	372.217	331.174	-2.378	-69.746
a_2	-37.975	-32.823	-7.497	5.416
a_3	3.381	2.650	1.342	-0.515
b_0	14.264	13.914	12.264	12.520
b_1	-0.748	-0.626	0.202	0.346
RMSE	0.00892	0.00667	0.03000	0.00674

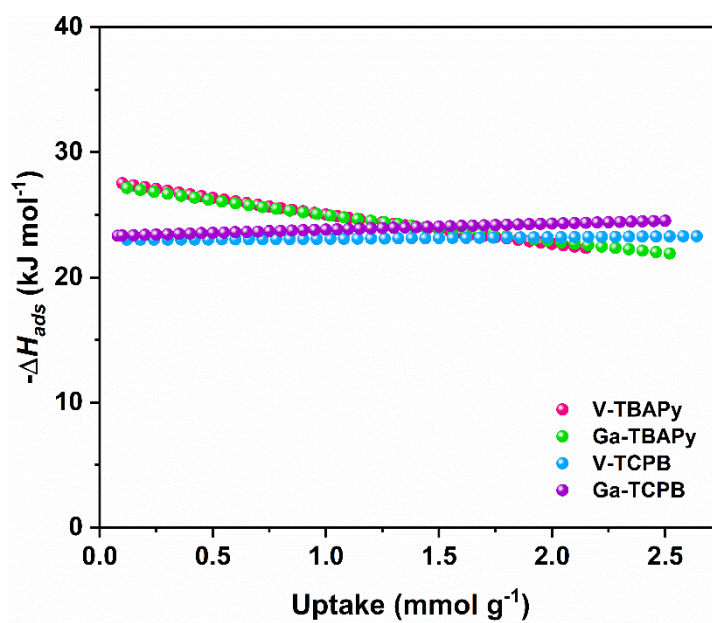


Fig. S29. Isosteric enthalpies of CO₂ adsorption ($-\Delta H_{ads}$) for V-, Ga-TBAPy and V-, Ga-TCPB.

Section S6.2. Gas selectivity

Section S6.2.1. Ideal (Henry's Law) selectivity

Ideal selectivities were calculated from pure-component CH₄, CO₂, N₂, and SF₆ isotherms at 293 K in the low-pressure region using the Henry's law constants ($s = K_{H, \text{gas}1} / K_{H, \text{gas}2}$).

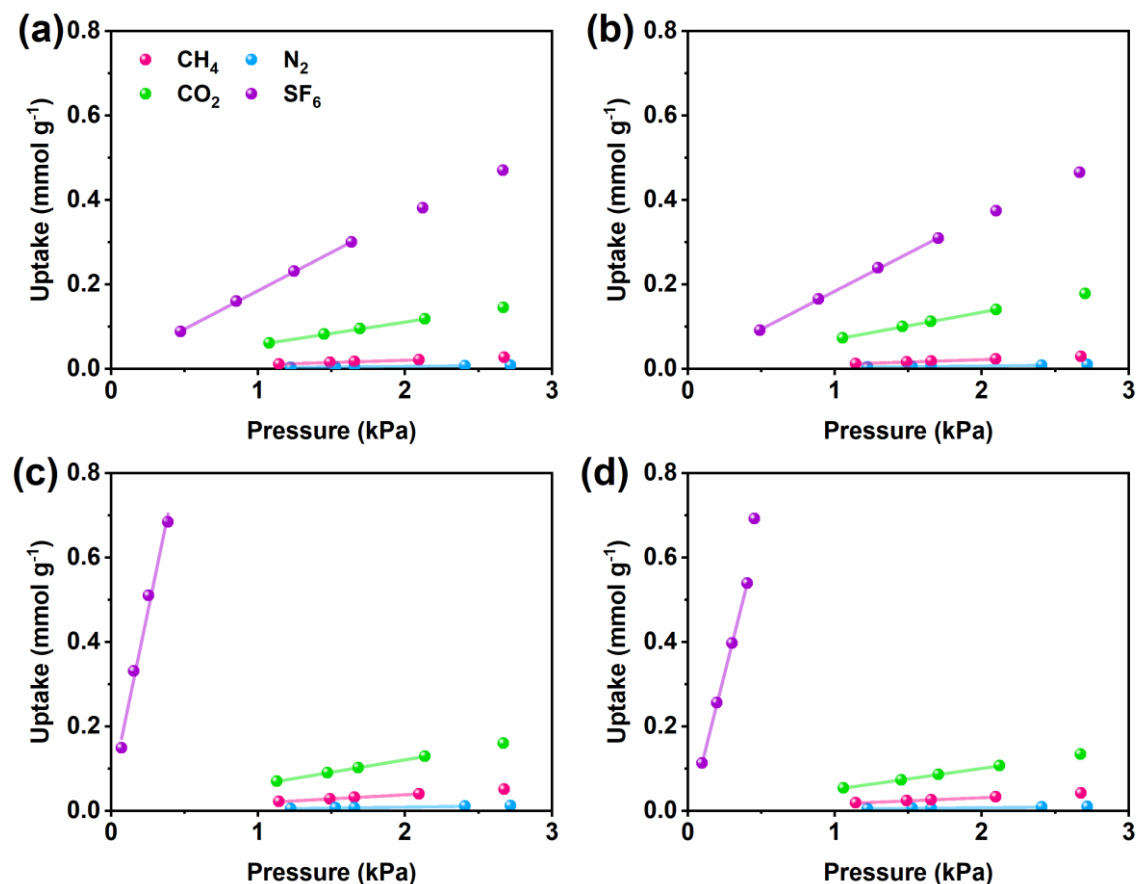


Fig S30. Linear fits of the CH₄, CO₂, N₂, and SF₆ adsorption isotherms recorded at 293 K in the low-pressure region of (a) V-TBAPy, (b) Ga-TBAPy, (c) V-TCPB, and (d) Ga-TCPB.

Table S12. Linear fitting parameters and calculated ideal SF₆/N₂, CO₂/N₂ selectivities from low-pressure data of CH₄, CO₂, N₂, and SF₆ adsorption isotherms recorded at 293 K of V-TBAPy.

Gas	Intercept (mmol g ⁻¹)	Slope (mmol g ⁻¹ kPa ⁻¹)	R ²	Ideal SF ₆ /N ₂ selectivity	Ideal CO ₂ /N ₂ selectivity
SF ₆	0.00442	0.18169	0.99977		
CO ₂	0.00453	0.05352	0.99982	53.75	15.83
CH ₄	0.00005	0.01053	1		
N ₂	0.00001	0.00338	1		

Table S13. Linear fitting parameters and calculated ideal SF₆/N₂, CO₂/N₂ selectivities from low-pressure data of CH₄, CO₂, N₂, and SF₆ adsorption isotherms recorded at 293 K of Ga-TBAPy.

Gas	Intercept (mmol g⁻¹)	Slope (mmol g⁻¹ kPa⁻¹)	R²	Ideal SF₆/N₂ selectivity	Ideal CO₂/N₂ selectivity
SF ₆	0.00534	0.17957	0.99954		
CO ₂	0.00627	0.06433	0.99948	47.51	17.02
CH ₄	0.00006	0.01126	1		
N ₂	0.00002	0.00378	1		

Table S14. Linear fitting parameters and calculated ideal SF₆/N₂, CO₂/N₂ selectivities from low-pressure data of CH₄, CO₂, N₂, and SF₆ adsorption isotherms recorded at 293 K of V-TCPB.

Gas	Intercept (mmol g⁻¹)	Slope (mmol g⁻¹ kPa⁻¹)	R²	Ideal SF₆/N₂ selectivity	Ideal CO₂/N₂ selectivity
SF ₆	0.05441	1.68071	0.98883		
CO ₂	0.00384	0.05873	0.99998	365.37	12.77
CH ₄	0.00019	0.01912	1		
N ₂	0.00002	0.00460	1		

Table S15. Linear fitting parameters and calculated ideal SF₆/N₂, CO₂/N₂ selectivities from low-pressure data of CH₄, CO₂, N₂, and SF₆ adsorption isotherms recorded at 293 K of Ga-TCPB.

Gas	Intercept (mmol g⁻¹)	Slope (mmol g⁻¹ kPa⁻¹)	R²	Ideal SF₆/N₂ selectivity	Ideal CO₂/N₂ selectivity
SF ₆	-0.01938	1.38600	0.99982		
CO ₂	0.00165	0.04963	0.99999	437.22	15.66
CH ₄	0.00195	0.01475	0.99857		
N ₂	0.00146	0.00317	0.98115		

Section S6.2.2. Ideal adsorption solution theory (IAST) selectivity

The pure-component SF₆ and N₂ isotherms recorded at 293 K were modeled using the Langmuir (Eq. 3) or dual-site Langmuir models (Eq. 4):

$$N_{eq} = \frac{N_{1,sat}b_1P}{1 + b_1P} \quad [3]$$

$$N_{eq} = \frac{N_{1,sat}b_1P}{1 + b_1P} + \frac{N_{2,sat}b_2P}{1 + b_2P} \quad [4]$$

Where N_{eq} (mmol g⁻¹) is the quantity of gas adsorbed under equilibrium at pressure P (kPa), $N_{1,sat}$ and $N_{2,sat}$ (mmol g⁻¹) are the maximum adsorption capacities of sites 1 and 2, and b_1 and b_2 (kPa⁻¹) are the Langmuir equilibrium constants.

IAST calculations were furthermore carried out for a theoretical gas mixture containing SF₆/N₂ (10:90) using the fitted isotherms in accordance with the IAST equations presented by Myers and Prausnitz²⁵.

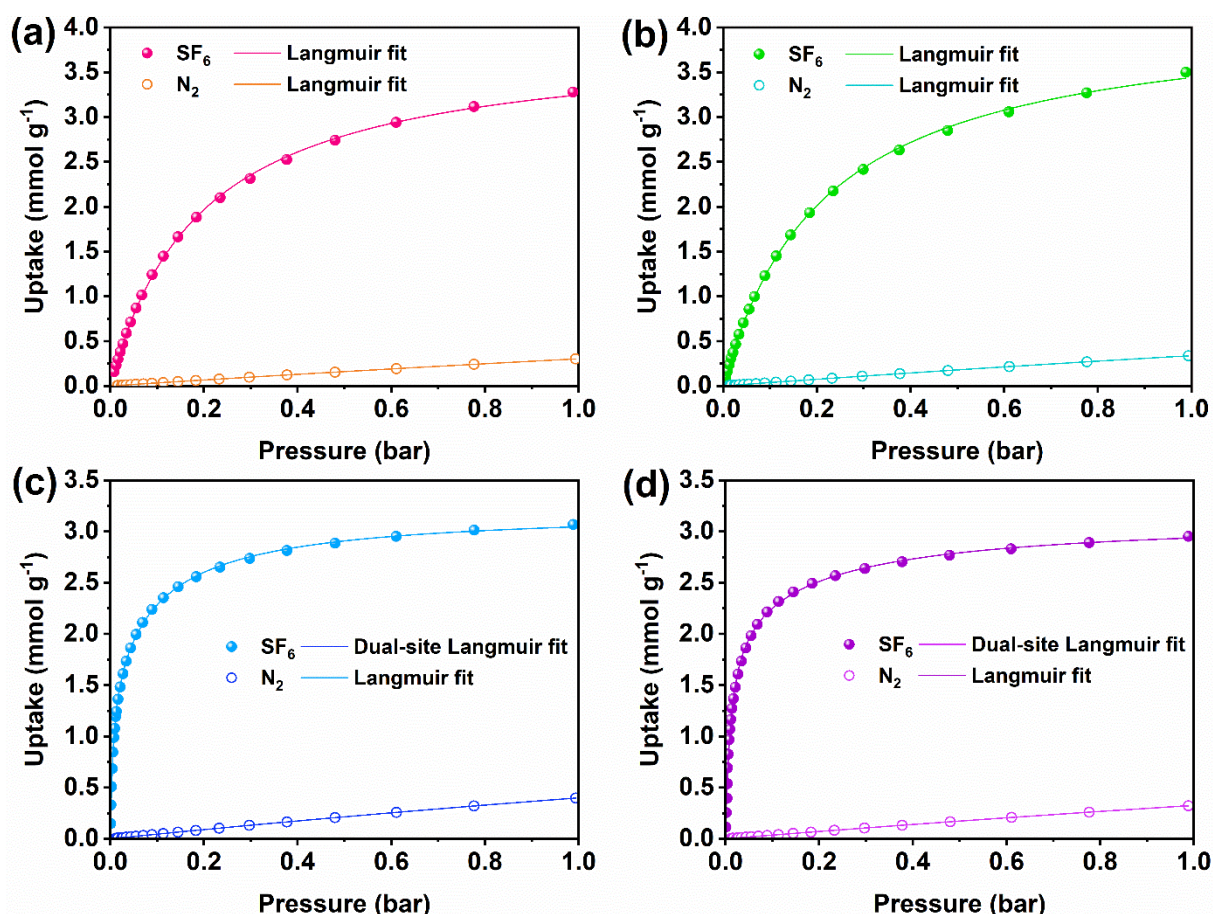


Fig. S31. Langmuir and dual-site Langmuir fits of CO₂ and N₂ adsorption isotherms recorded at 293 K for (a) V-TBAPy, (b) Ga-TBAPy, (c) V-TCPB, and (d) Ga-TCPB.

Table S16. Langmuir and dual-site Langmuir fitting parameters for CO₂ adsorption isotherms recorded at 293 K of V-TBAPy, Ga-TBAPy, V-TCPB, and Ga-TCPB.

	V-TBAPy	Ga-TBAPy	V-TCPB	Ga-TCPB
$N_{1,sat}$ (mmol g ⁻¹)	3.87684	4.18311	1.58472	2.16207
b_1 (bar ⁻¹)	5.15984	4.64016	162.92417	91.00422
$N_{2,sat}$ (mmol g ⁻¹)	-	-	1.62618	0.97692
b_2 (bar ⁻¹)	-	-	9.49274	4.51466
<i>RMSE</i>	0.01834	0.01953	0.01220	0.03609

Table S17. Langmuir fitting parameters for N₂ adsorption isotherms recorded at 293 K of V-TBAPy, Ga-TBAPy, V-TCPB, and Ga-TCPB.

	V-TBAPy	Ga-TBAPy	V-TCPB	Ga-TCPB
$N_{1,sat}$ (mmol g ⁻¹)	2.86370	3.12058	2.95920	2.92551
b_1 (bar ⁻¹)	0.11813	0.12150	0.15631	0.12558
<i>RMSE</i>	0.00012	0.00010	0.00002	0.00001

Section S7. SF₆ and CO₂ temperature-swing adsorption cycling

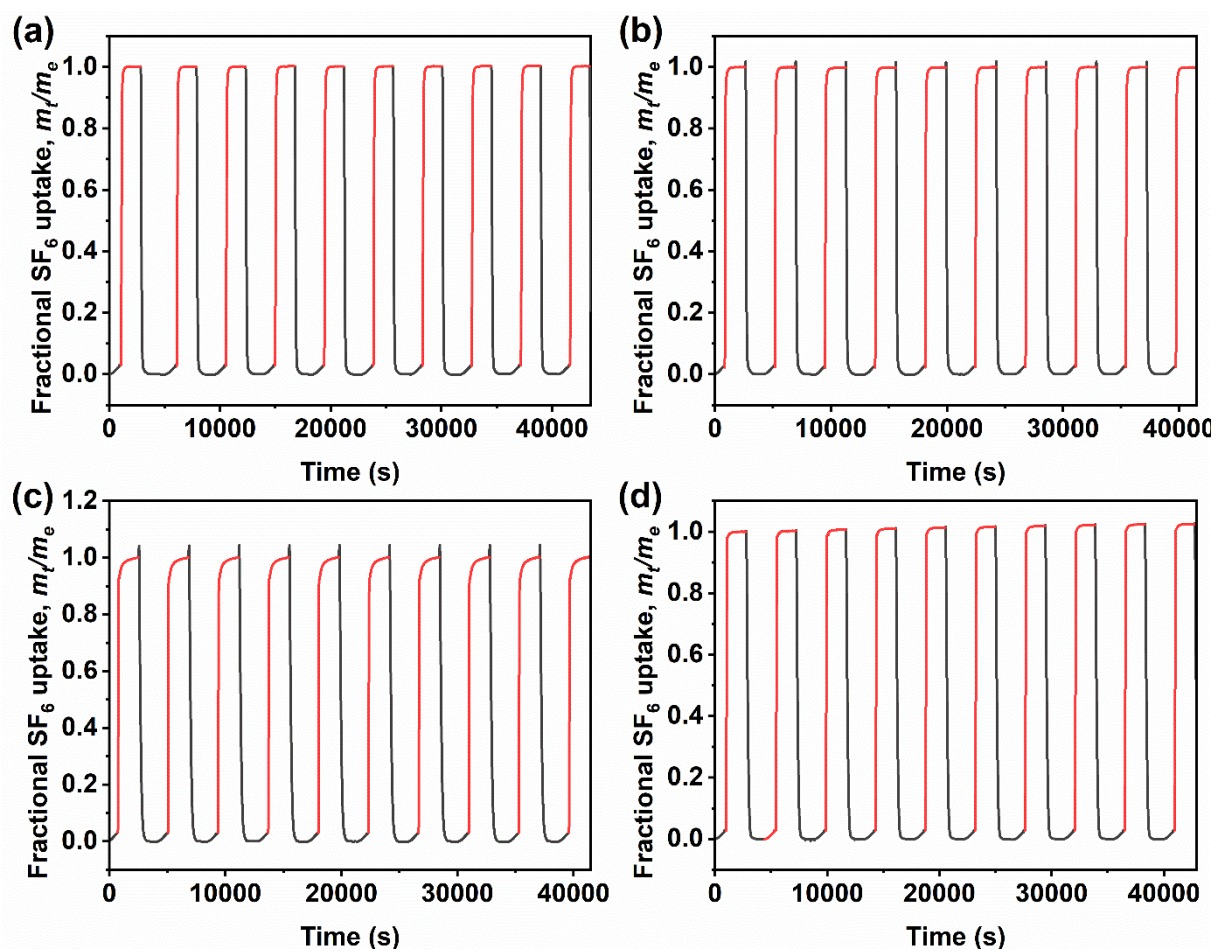


Fig. S32. Gravimetric temperature-swing adsorption cycling of SF₆ on (a) V-TBAPy, (b) Ga-TBAPy, and (c) Ga-TBAPy. The adsorption and desorption part of the cycles are highlighted in red and black, respectively.

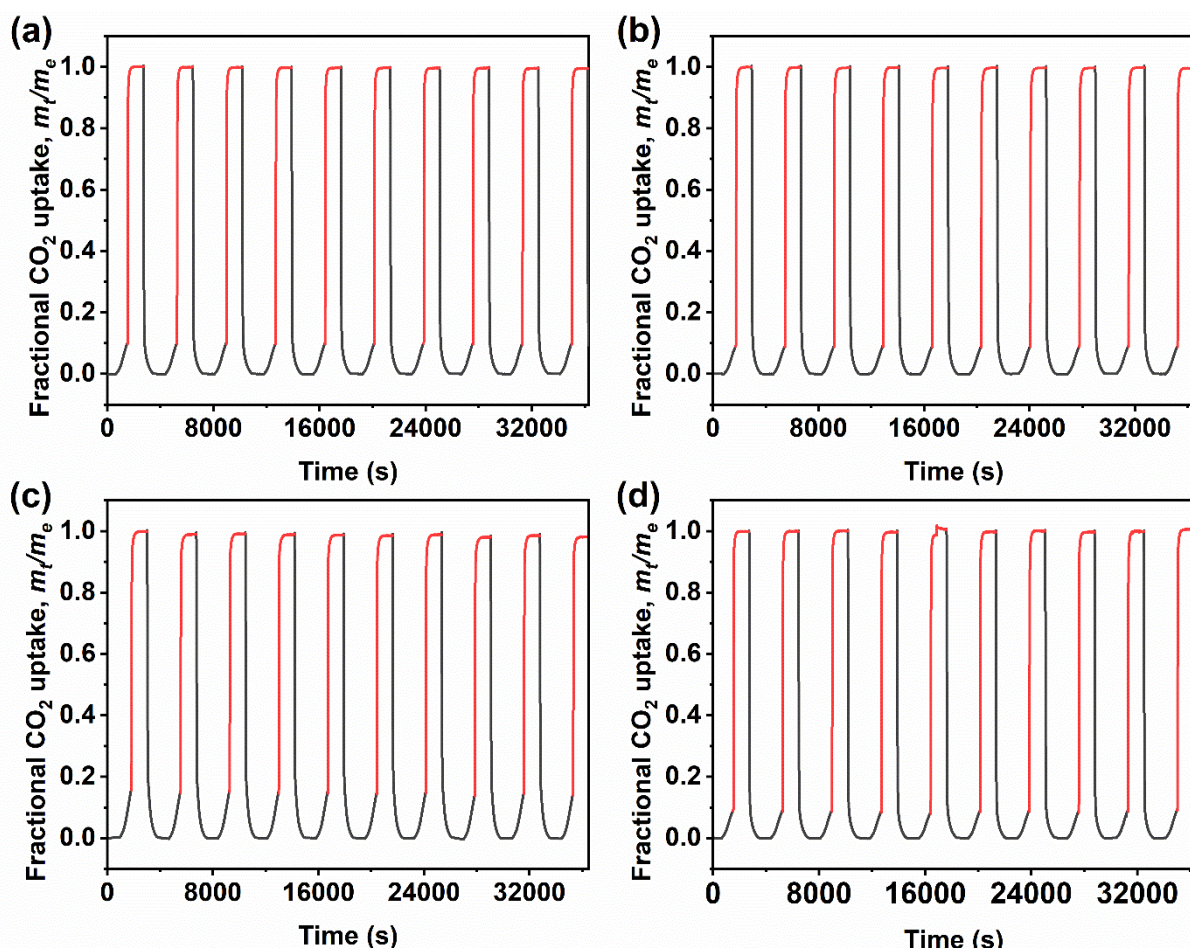


Fig. S33. Gravimetric temperature-swing adsorption cycling of CO₂ on (a) V-TABPy, (b) Ga-TBAPy, (c) V-TCPB, and (d) Ga-TCPB. The adsorption and desorption part of the cycles are highlighted in red and black, respectively.

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